

# Next Generation 인터페이스 테크놀로지 트렌드

(USB3.1, HDMI2.0, MHL3.2)

텍트로닉스  
박영준 부장

*WIDER  
DEEPER*

2015 Tektronix Innovation Forum

# Agenda

- USB3.1 Compliance Test update
  - What's different for USB3.1
  - Transmitter and Receiver Compliance Test
- HDMI2.0, MHL3.2 overview
- Q & A

# What's different for USB3.1



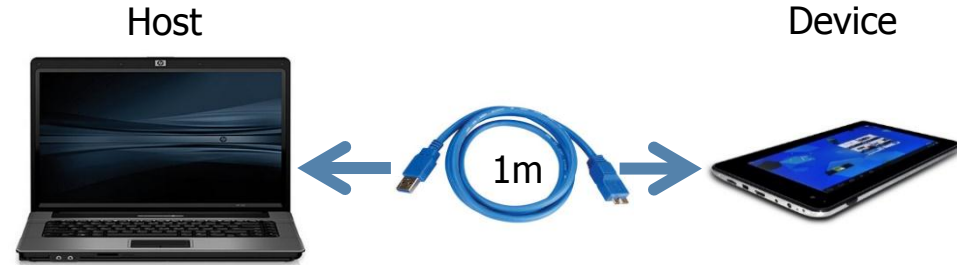
# USB 3.1 Comparison

	Gen1	Gen2
<b>Data Rate</b>	5 Gb/s	10 Gb/s
<b>Encoding</b>	8b/10b	128b/132b
<b>Target Channel</b>	3m + Host/ Device channels (-17dB, 2.5 GHz)	1m + board ref channels (-23dB, 5 GHz)
<b>LTSSM</b>	LFPS, TSEQ, TS1, TS2	LFPSPlus, SCD, TSEQ, TS1, TS2,
<b>Reference Tx EQ</b>	De-emphasis	3-tap (Preshoot/De-emphasis)
<b>Reference Rx EQ</b>	CTLE	CTLE(6 level) + 1-tap DFE
<b>JTF Bandwidth</b>	4.9 MHz	7.5 MHz
<b>Eye Height (TP1)</b>	100 mV	70 mV
<b>TJ@BER</b>	132 ps (0.66 UI)	71 ps (0.714 UI)
<b>Backwards Compatibility</b>	Y	Y
<b>Connector</b>	Std A	Improved Std A with insertion detect

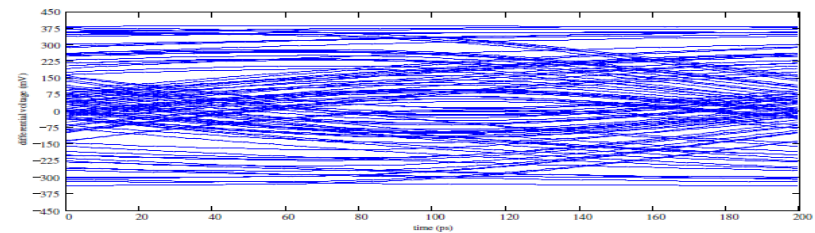
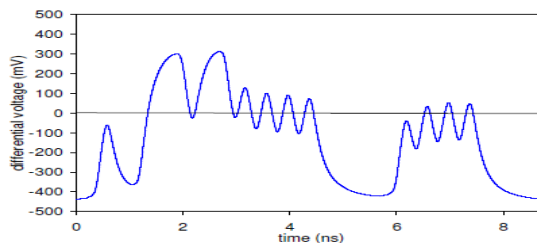
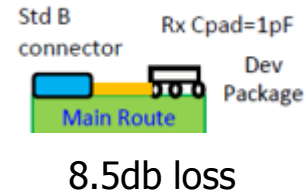
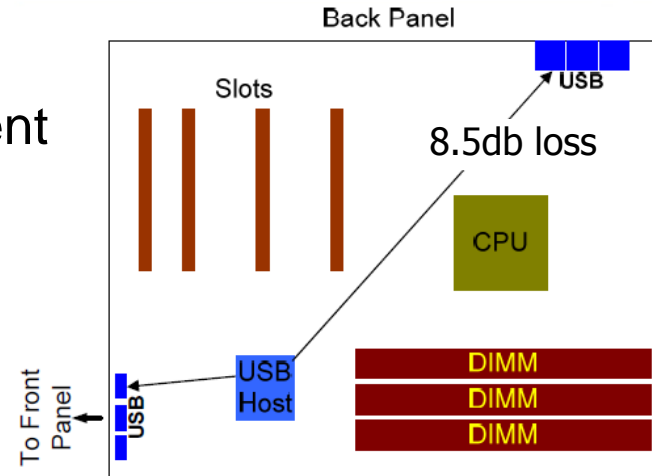
\* SCD: Speed Capability Declaration

# USB 3.1 Key Considerations – Long Channel

- Channel characteristics
  - 8.5dB loss host PCB route
  - 8.5dB loss device PCB route
  - 1m cable

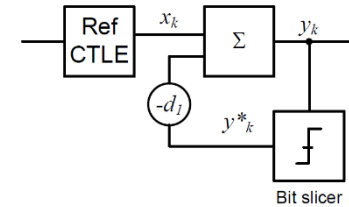
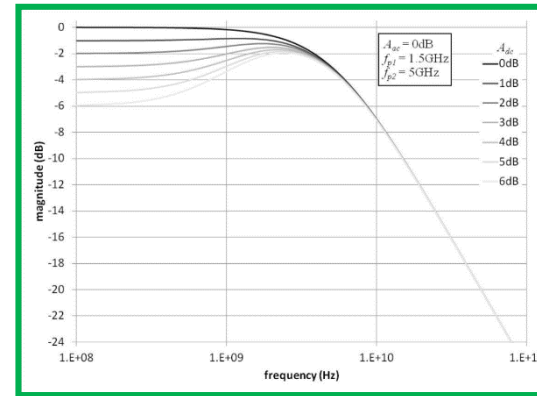
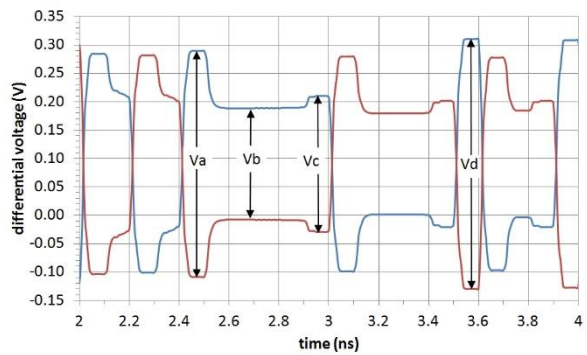


- Cause Frequency dependent loss (ISI) and Crosstalk
- Close the 10Gb/s eye



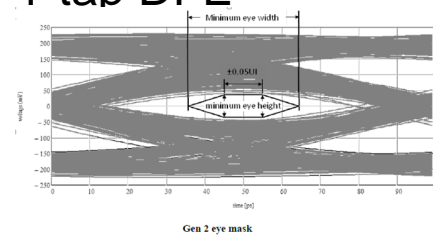
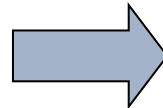
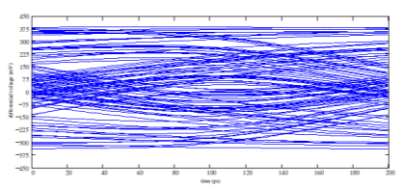
Source: USB DevCon

# USB 3.1 Key Considerations – TX,RX Equalization



- Transmitter Equalization
  - 2.2 dB Preshoot
  - -3.1 dB De-emphasis

- Receiver Equalization
  - multiple CTLE gain settings
  - 1-tap DFE



► Enable to open Receiver eye

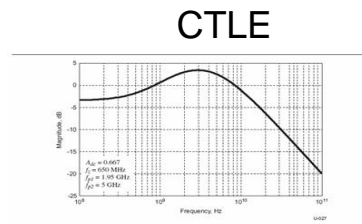
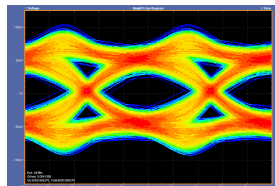
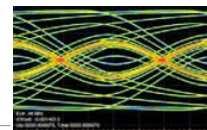
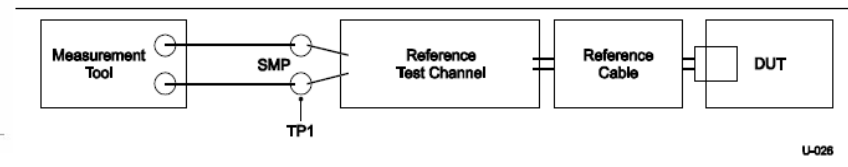
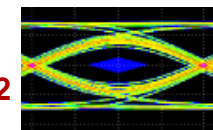


Figure 6-17. Tx Compliance Rx EQ Transfer Function



TP1 Transmit Channel TP2

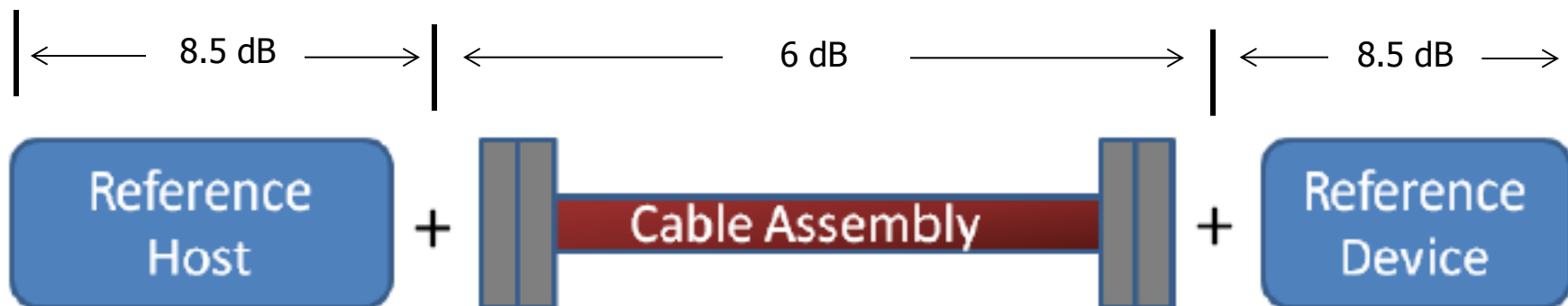


U-028

Figure 6-19. Tx Normative Setup with Reference Channel

# New Channel Budget of USB3.1

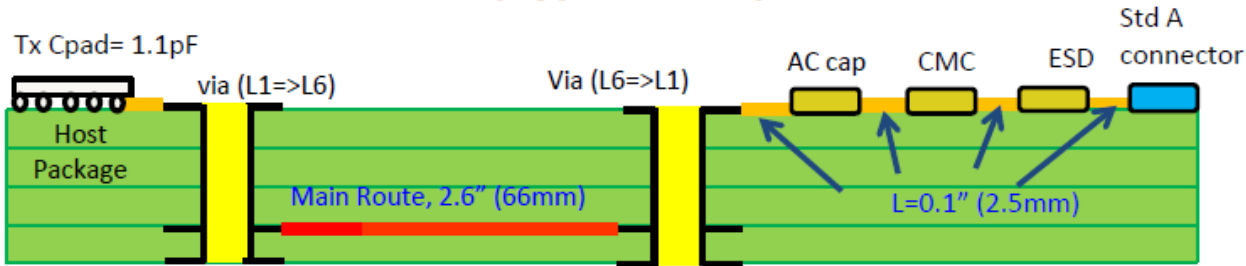
- Target **23 dB** @ 5 GHz loss budget (die-to-die)
- Equal channel allocation for host/device
- Tx EQ settings recommended (**normative**)
  - **2.2 dB** Preshoot and **-3.1 dB** De-emphasis
  - Requires **additional compliance patterns** for Tx testing
- Host or device loss that exceeds **8.5dB** may required repeater
  - Need end-to-end training -> link aware repeaters



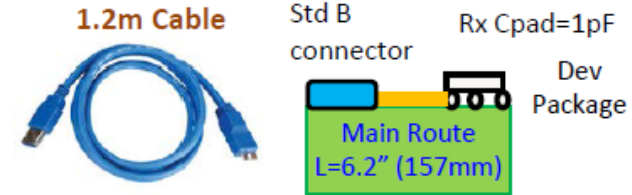
\* Items in red indicate new as Aug 2014 release

# 23 dB Reference Channel Loss

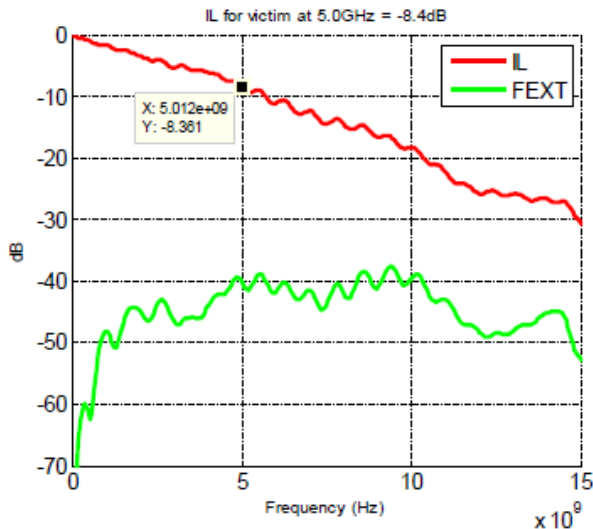
## Host (Type 3 PCB)



## Dev (Type 3 PCB)

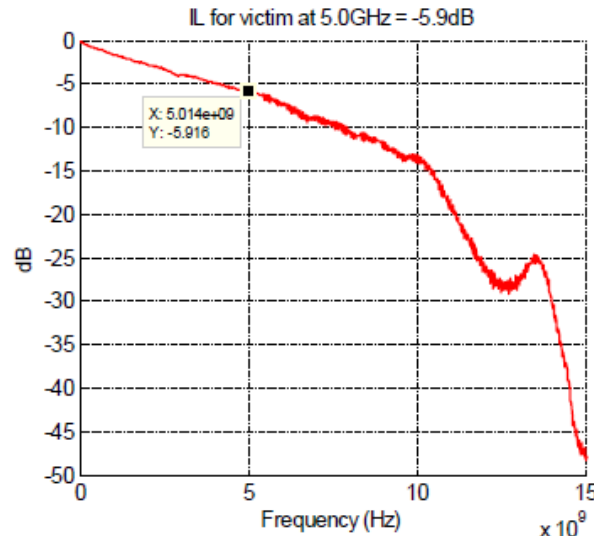


## 8.5dB Host

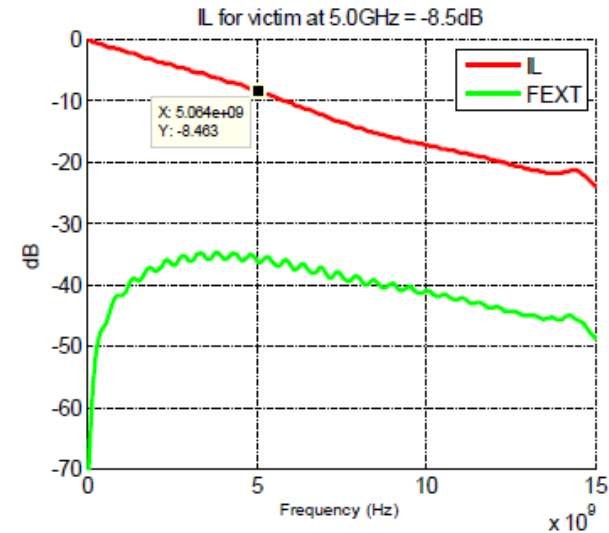


## 6dB Cable

(with mated connectors)



## 8.5dB Device



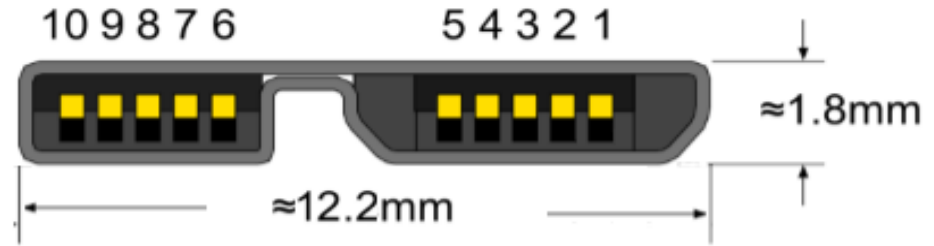
Source: USB-IF Developer Training



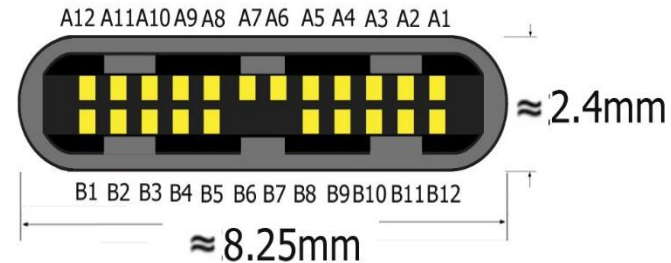
# Type-C Comparison

- Rounded, reversible, flip-able
- ~25% less width vs.  $\mu$ B
- Signaling
  - Two SS differential pairs
  - Vbus power
  - Configuration Channel (CC)
  - USB 2.0 differential pair
  - Plug power (Vconn)

## Micro B Plug



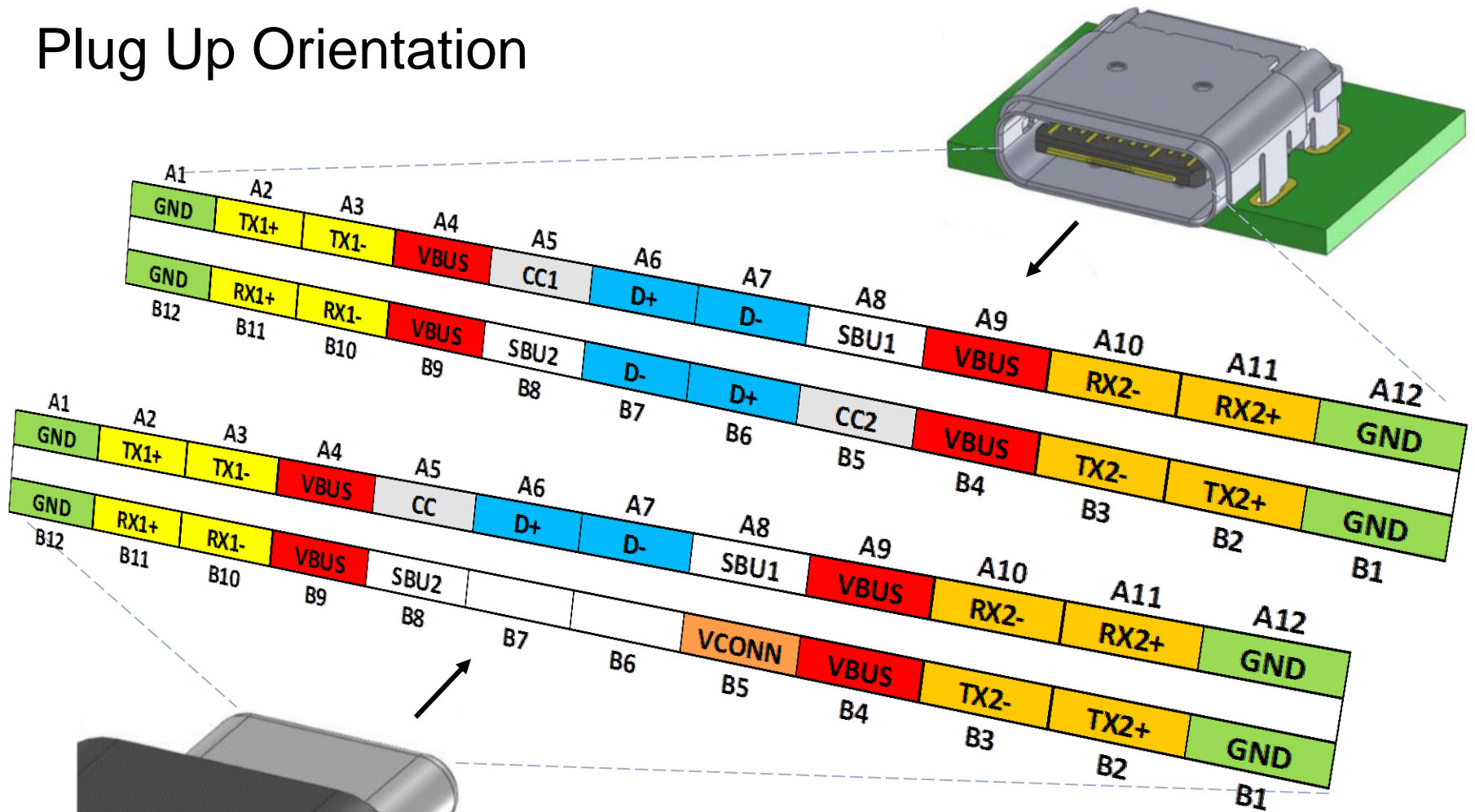
## Type-C Plug



A1	A2	A3	A4	A5	A6	A7	A8	A9	A10	A11	A12
GND	TX1+	TX1-	VBUS	CC	D+	D-	SBU1	VBUS	RX2-	RX2+	GND
GND	RX1+	RX1-	VBUS	SBU2			VCONN	VBUS	TX2-	TX2+	GND
B12	B11	B10	B9	B8	B7	B6	B5	B4	B3	B2	B1

\* New signals

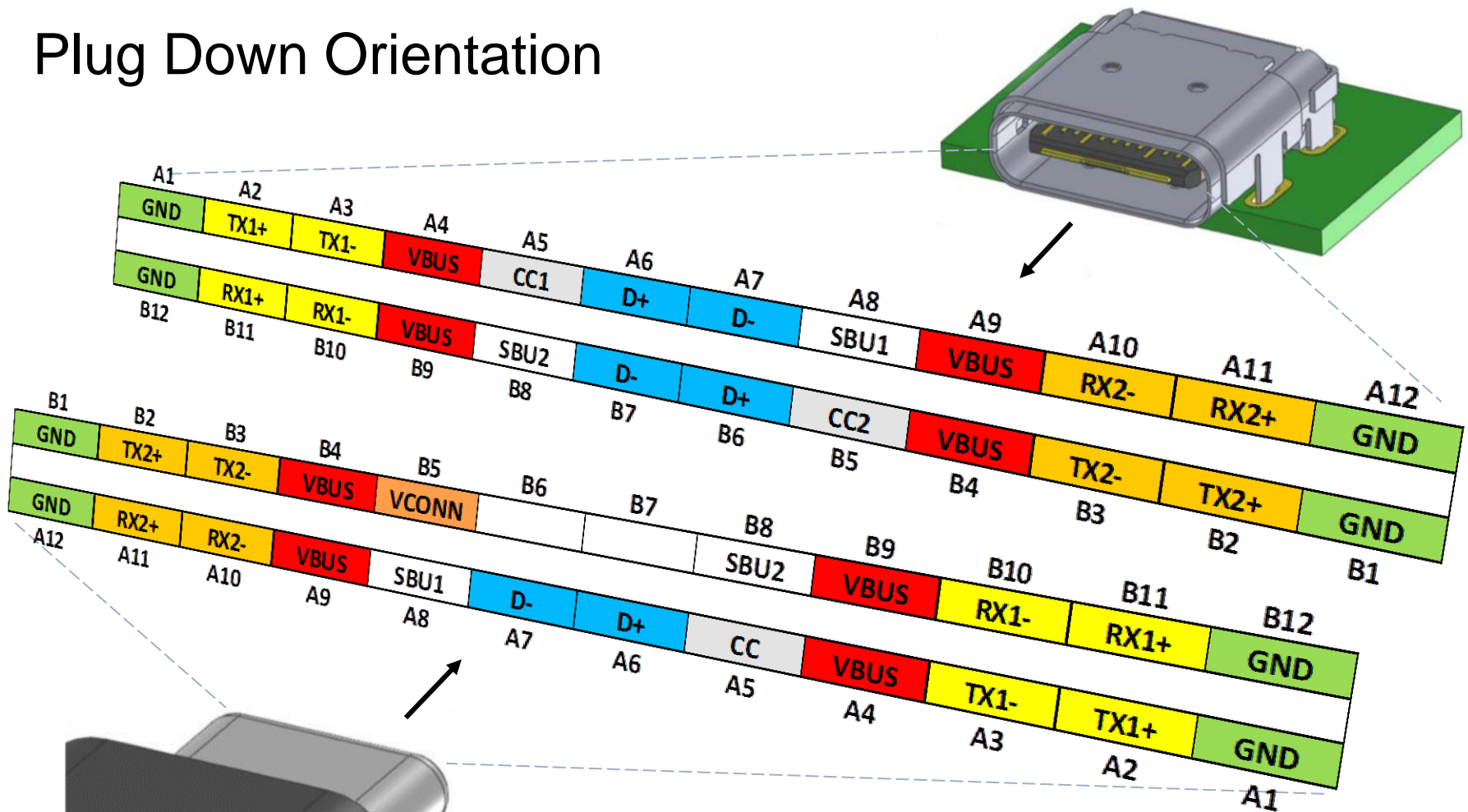
# Plug Up Orientation



## “Upside Up”

Note, end-to-end signaling have swapped pairs (e.g. Host\_A2 ( TX1+ ) → Device\_A11 ( RX2+ ))

# Plug Down Orientation



**“Upside Down”** (both plugs flipped)

Note, end-to-end signaling have swapped pairs  
 (e.g. Host\_A2 ( TX1+ ) ↔ Device\_A11 ( RX2+ ))

# Connector Transition

## Legacy Cables

Plug 1	Plug 2	Version	Length
A	C	USB 2.0	≤ 4m
A	C	USB 3.1 Gen2	≤ 1m
C	B	USB 2.0	≤ 4m
C	B	USB 3.1 Gen2	≤ 1m
C	Micro-B	USB 2.0	≤ 2m
C	Micro-B	USB 3.1 Gen2	≤ 1m

## Defined Adapters

Plug 1	Plug 2	Version	Length
C	Micro-B	USB 2.0	≤ 0.15 m
C	A	USB 3.1 Gen1	≤ 0.15 m

Host (Type-C)



Cable  
(C to Micro-B)

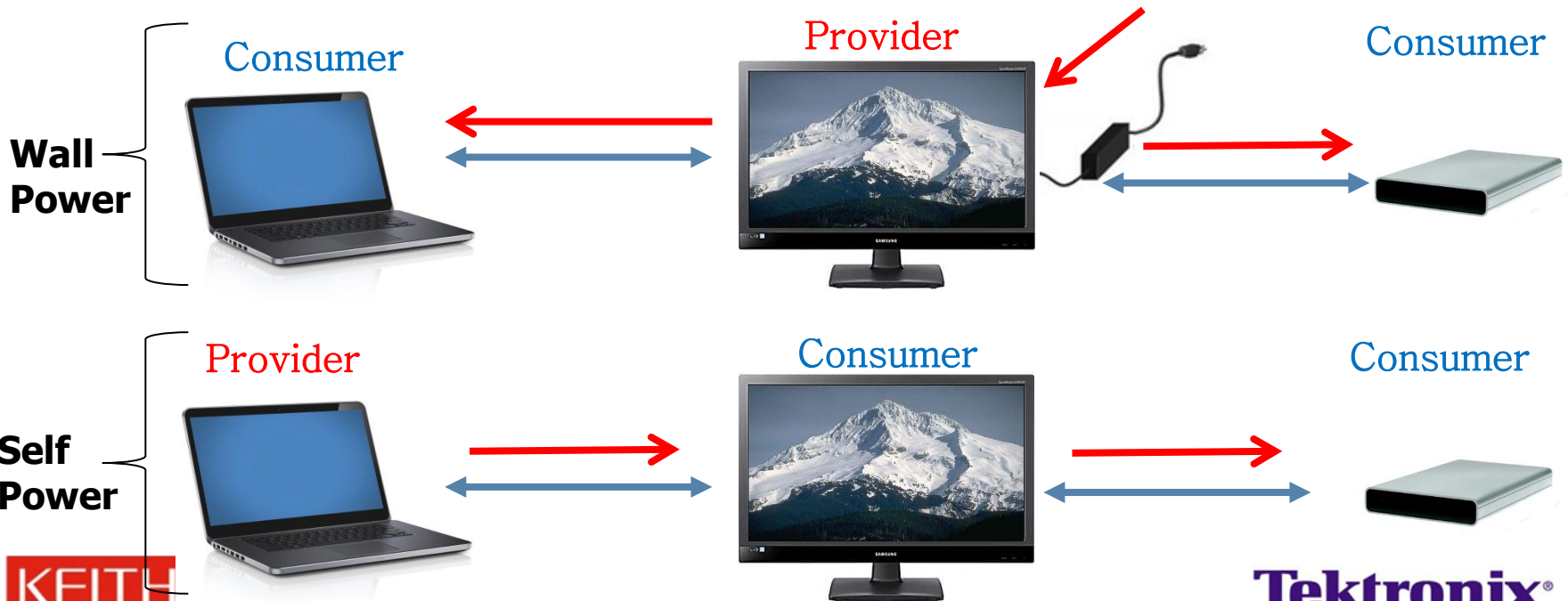


Device  
(Micro-B)



# USB Power

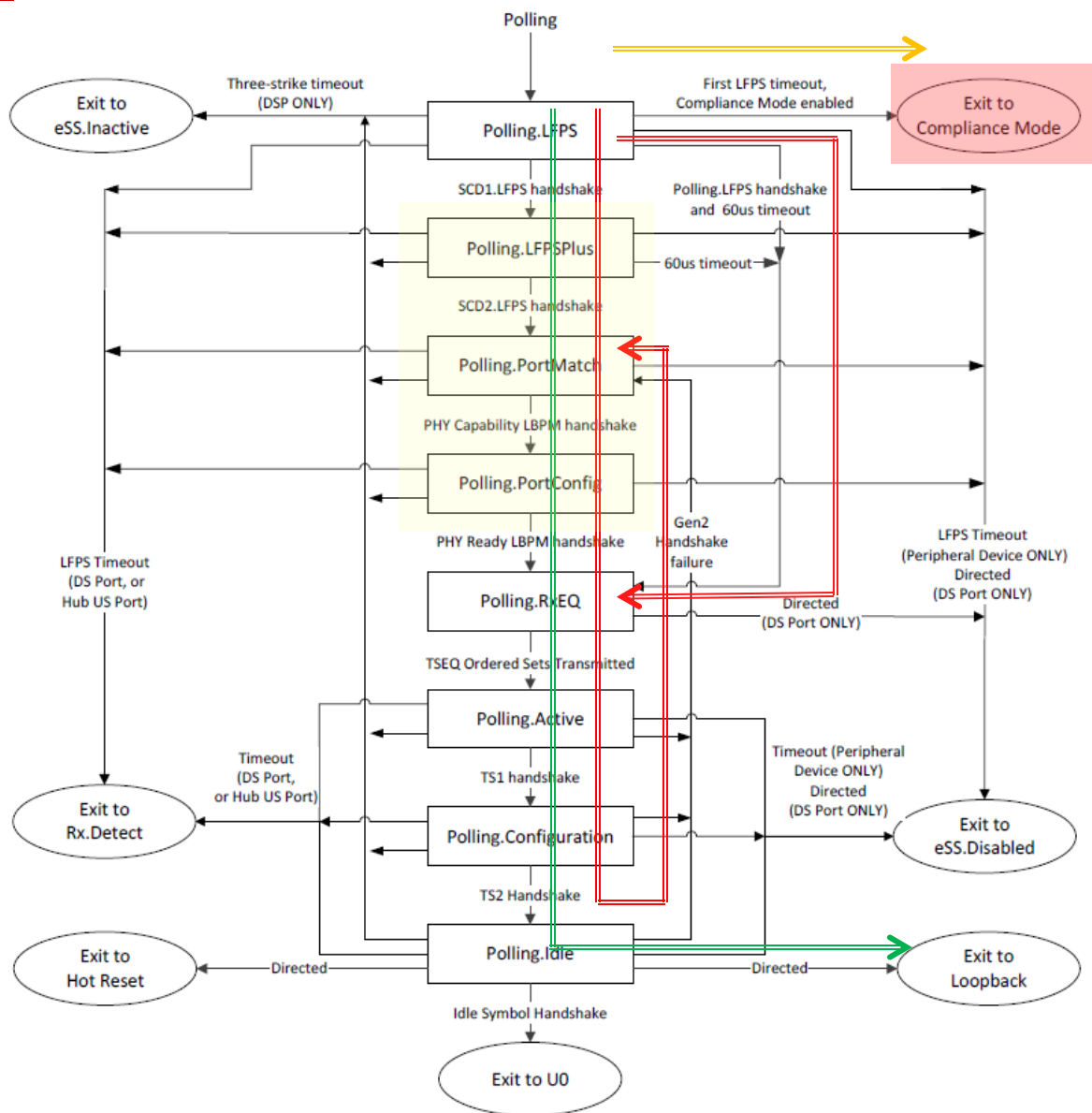
- **USB 3.0** power handling -> Up to 900 mA (Nov 2008)
- **Battery Charging** (BC 1.2, Dec 2010)
  - Increases charging of up to 1.5 A
  - No simultaneous data transfer in high power mode
- **Power Delivery** (PD 2.0, August 2014) specification
  - Up to 100W with switchable power delivery source
  - Switchable power delivery source without changing cable direction



# Transmitter Compliance Test



# Entering to Compliance Mode for Transmitter test – Compliance TX



Successful Gen2 link training with loopback asserted – Enter in Loopback mode

No link partner response – Enter Tx compliance mode

Training failure – Retry at Gen1 rate

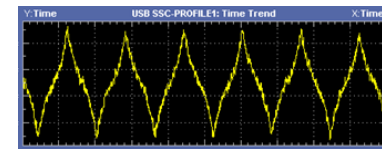
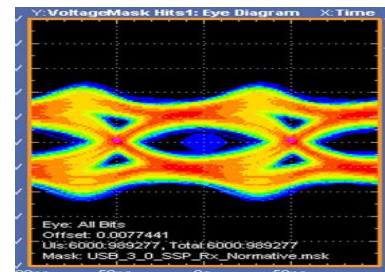
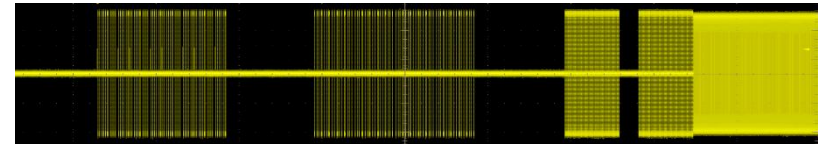
LFPS detected but no LFPSPlus - Train at Gen1 rate

# USB3.1 Transmitter Compliance Testing Patterns

Table 6-13. Compliance Pattern Sequences

Compliance Pattern	Value	Description
CP0	D0.0 scrambled	A pseudo-random data pattern that is exactly the same as logical idle (refer to Chapter 7) but does not include SKP sequences.
CP1	D10.2	Nyquist frequency
CP2	D24.3	Nyquist/2
CP3	K28.5	COM pattern
CP4	LFPS	The low frequency periodic signaling pattern
CP5	K28.7	With de-emphasis
CP6	K28.7	Without de-emphasis
CP7	50-250 1's and 0's	With de-emphasis. Repeating 50-250 1's and then 50-250 0's.
CP8	50-250 1's and 0's	With without de-emphasis. Repeating 50-250 1's and then 50-250 0's.
CP9		Pseudo-random data pattern (see section 6.4.4.1)
CP10	AAh	Nyquist pattern at 10Gb/s. This is not 128b132b encoded.
CP11	CCh	Nyquist/2 at 10Gb/s, This is not 128b132b encoded.
CP12	LFSR15	Uncoded LFSR15 for PHY level testing and fault isolation. This is not 128b132b encoded.

Note: Unless otherwise noted, scrambling is disabled for compliance patterns.]

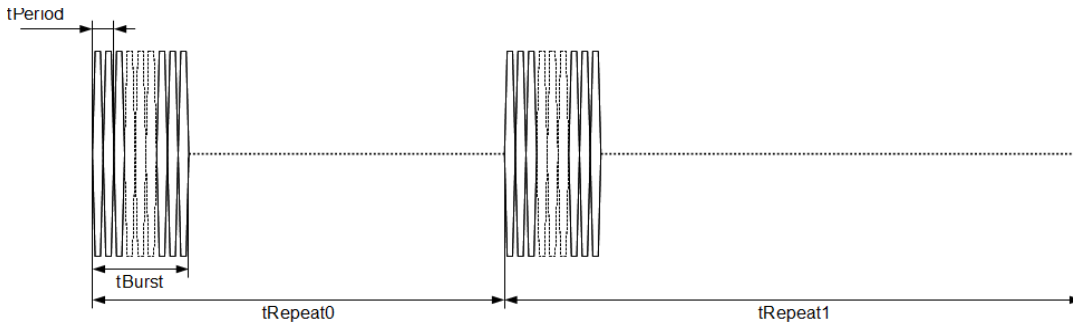


- **LFPS, CP9, CP10 are used for Compliance testing for TX**
- CP0 through CP8 are transmitted at Gen 1 rate, while **CP9 through CP12 are transmitted at Gen 2 rate.**
- Gen 2 compliance pattern comprises a pseudo-random data pattern
- The pattern repeats every 65536 symbols and starts with a SYNC Ordered Set



# LFPS plus Encoding for USB3.1

## LFPS



## LFPS Based PWM Signaling (LBPM)

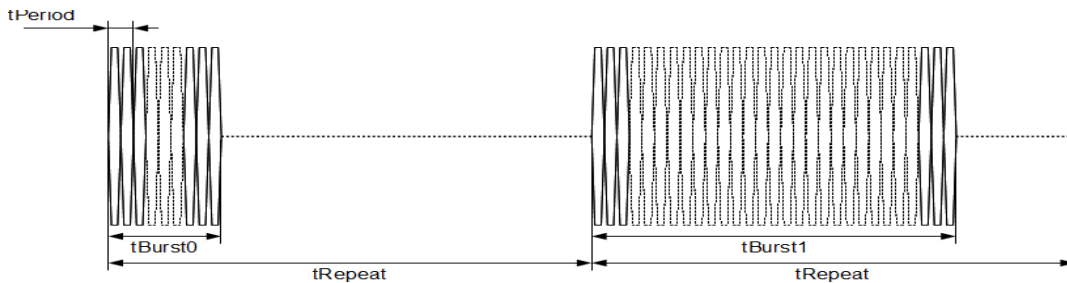
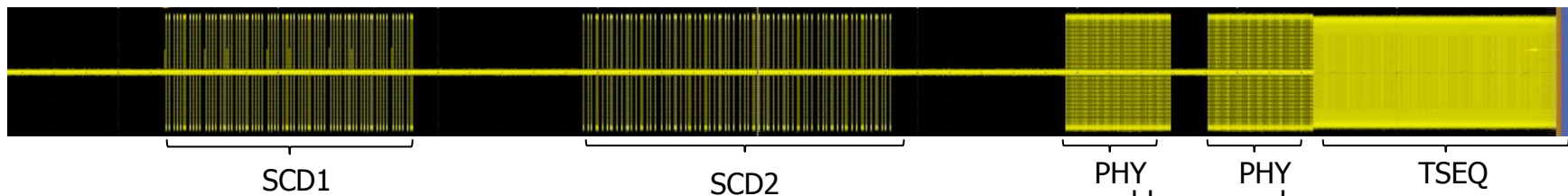


Table 6-31. Binary Representation of Polling.LFPS

$t_{Repeat}$ (us)	Logic value
6~9	'0'
11~14	'1'
9~11	illegal

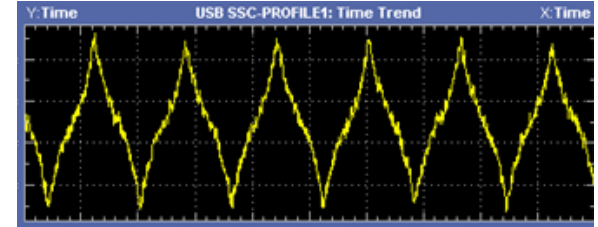
- SuperSpeed+ identity check
- $t_{Repeat}$  Modulation
- SCD1.LFPS (4'b0010)
- SCD2.LFPS (4'b1101)
- Rate (speed and lane) announcement and negotiation
- Repeater declaration
- Power state transition in repeater



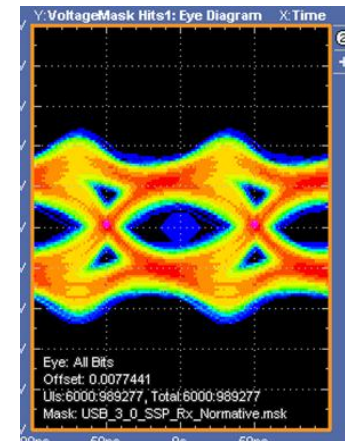
# USB 3.1 Transmitter Measurement Overview

Spec Reference	Parameter
Table 6-16	SSC Modulation Rate SSC Deviation
Table 6-17	Unit Interval including SSC Maximum Slew Rate (5 GT/s) SSC $df/dt$ (10 GT/s)
Table 6-17	Differential p-p Tx Voltage Swing Low-power Differential p-p Tx Voltage Swing De-emphasized Output Voltage Ratio (5 GT/s)
Table 6-18	Tx Min Pulse Deterministic Min Pulse Transmitter DC Common Mode Voltage Tx AC Common Mode Voltage Active
Table 6-19	Transmitter Eye RJ/DJ/TJ - Dual Dirac at 10-12 BER
Table 6-28	LFPS Common Mode Voltage LFPS Differential Voltage LFPS Rise Time LFPS Fall Time LFPS Duty Cycle LFPS tPeriod LFPS tPeriod-SSP (10 GT/s)
Table 6-29	LFPS tBurst LFPS tRepeat
Table 6-31	LFPS tRepeat-0 (10 GT/s) LFPS tRepeat-1 (10 GT/s)
Table 6-32	LFPS Pulse Width Modulation (10 GT/s) tLFPS-0 (10 GT/s) tLFPS-1 (10 GT/s)

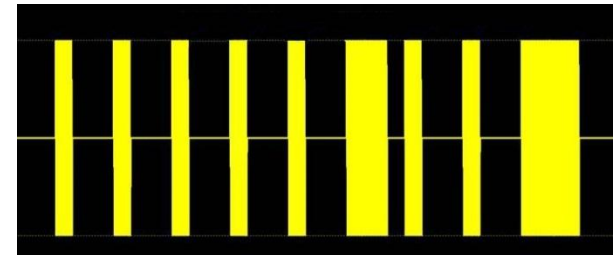
**Clock**  
(CP10)



**PHY**  
(CP9)\*



**LFPS**



# USB3.1 Transmitter Compliance Testing

1. Connect DUT to scope via test fixture.
2. Transmit CP10 (clock) & measure  $10^6$  consecutive UI
  - This step used to measure RJ
  - Requires toggling from default CP0 up to CP10
3. Repeat with CP9 (scrambled data pattern)
  - Will combine RJ (step 2) with DJ to extrapolate TJ (step5)
4. Post-process the waveforms with the compliance channel, the reference CTLE, & jitter transfer function
  - Channels are S-Parameter-based and are embedded into captured waveform
5. Extrapolate jitter to  $10^{-12}$  BER

Spec	Min	Max	Units
Eye Height	70	1200	mV
Dj @ $10^{-12}$ BER		0.530	UI
Rj @ $10^{-12}$ BER		0.184	UI
Tj @ $10^{-12}$ BER		0.714	UI

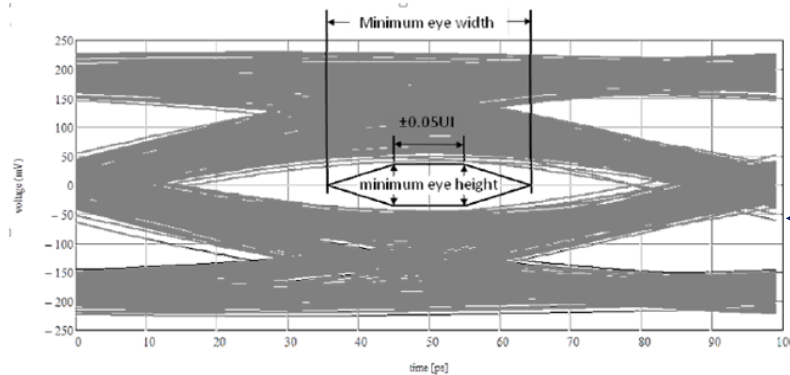
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Note: Unless otherwise noted, scrambling is disabled for compliance patterns.]

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- Gen 2 compliance pattern comprises a pseudo-random data pattern
- The pattern repeats every 65536 symbols and starts with a SYNC Ordered Set



Gen 2 eye mask

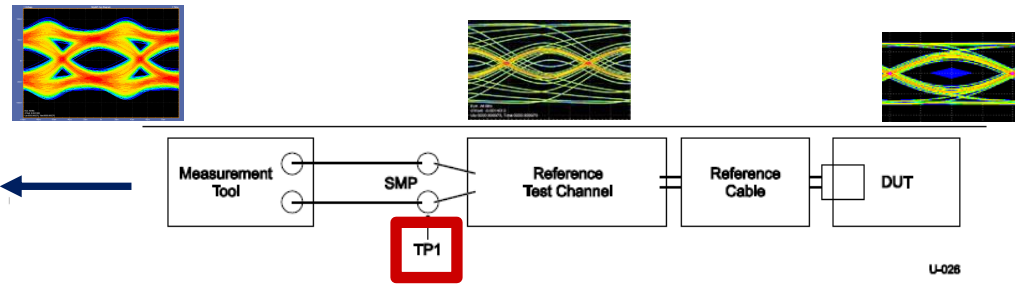
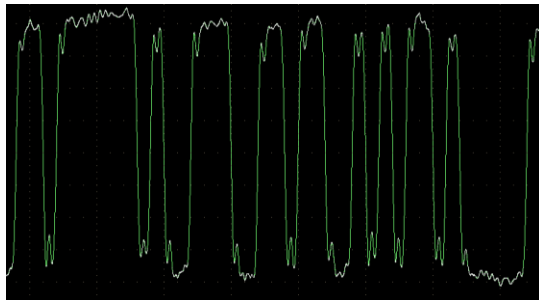
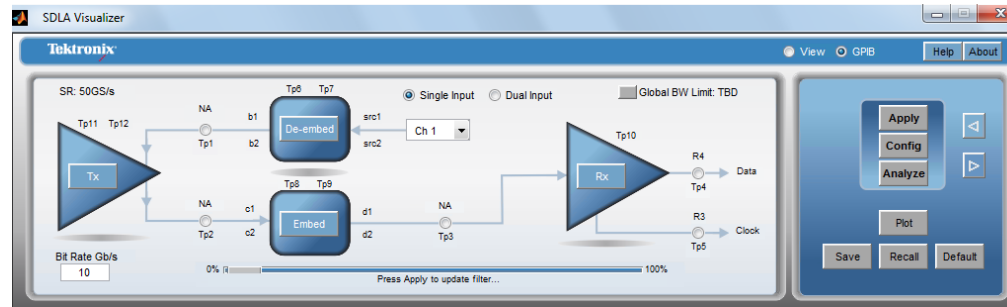


Figure 6-19. Tx Normative Setup with Reference Channel

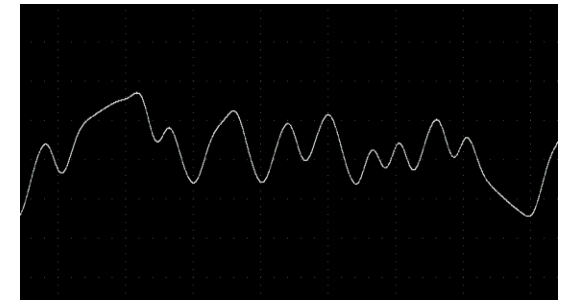
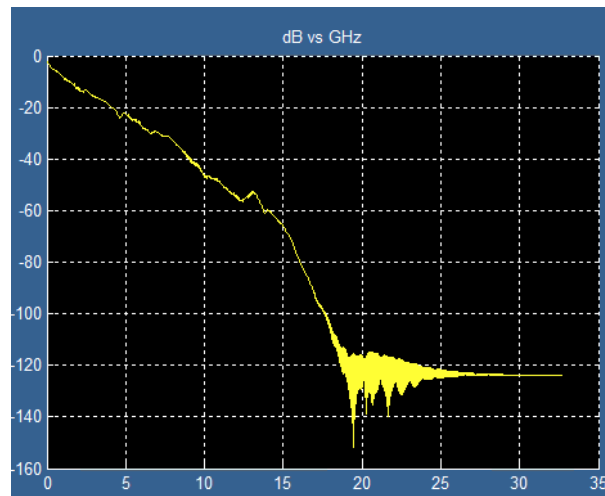
# Transmitter Capture and Channel Embed

- Capture CP9 (data) and CP10 (clock)
- Input reference channel models



CP9 Scrambled Pattern (TP0)

Reference Channel



CP9 Scrambled Pattern (TP1)

# Reference Tx Equalization

- USB channel profiles are dynamic (consumer)
- Need flexible solution space for link optimization
- Below are recommended Tx settings for good margin with target reference channels

Host/Device Loss	<3.5dB	≥3.5dB
$C_{-1}$	0.000	-0.125
$C_1$	-0.100	-0.125
$V_a/V_d$	1.00	0.80
$V_b/V_d$	0.75	0.55
$V_d/V_d$	0.75	0.75

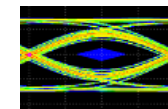
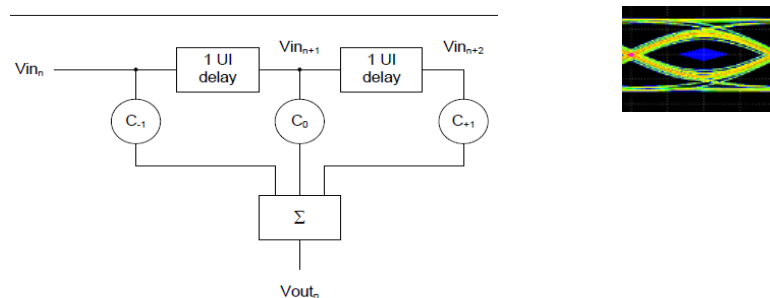
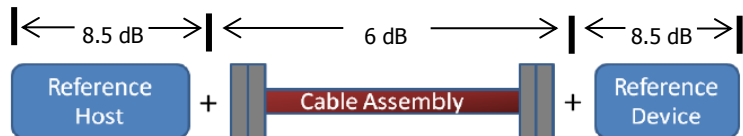
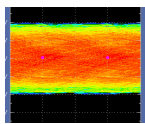
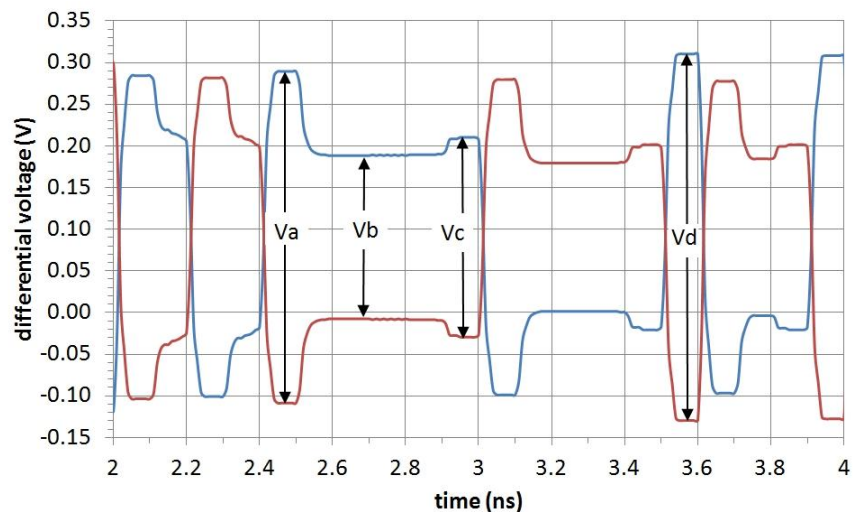
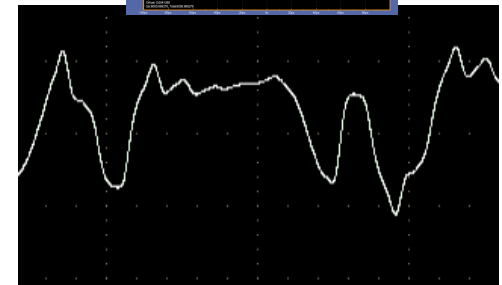
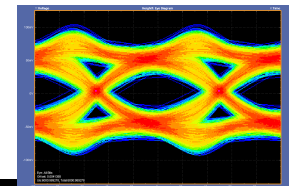
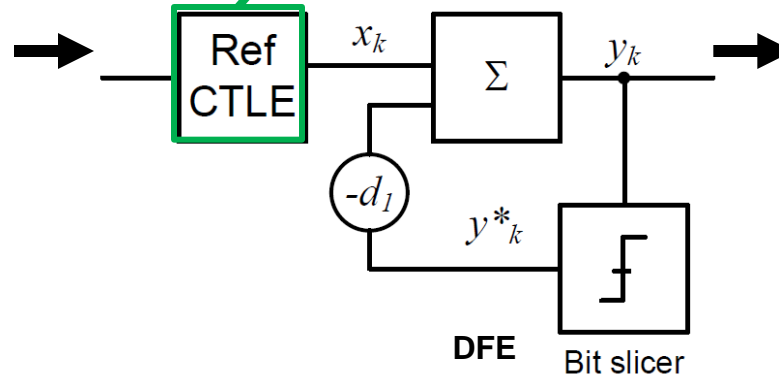
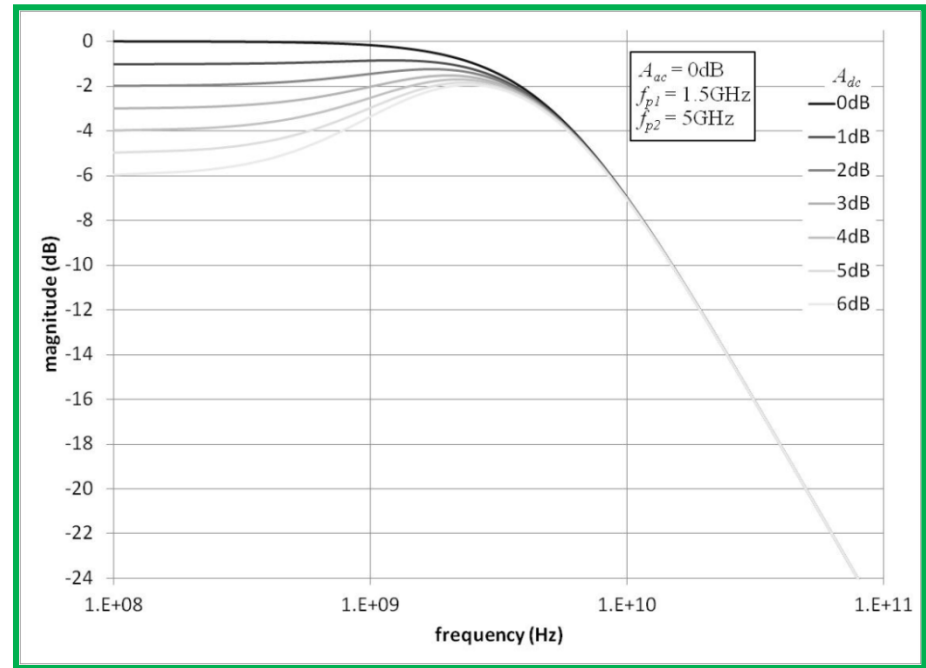
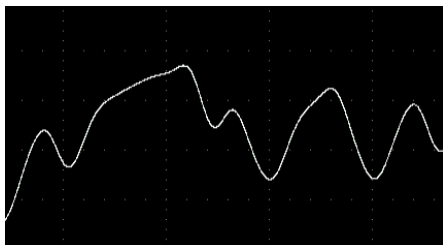
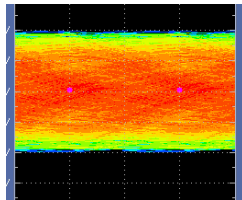


Figure 6-21. 3-tap Transmit Equalizer Structure

# Reference RX Equalizer

- Far End (TP1) Eye closed
- Need to open eye with EQ
- Adaptation only for Rx
  - No back channel Tx negotiation
- Iterate through multiple CTLE gain settings + 1-tap DFE



# Transmitter Validation Example

- Find optimum Eye height vs. Rx EQ –CTLE and DFE

SDLA Visualizer - Rx Configuration

Single run completed.

User  
 AMI  
 Thru

Config  
Taps  
TrainSeq  
Error Log

On Equalizer: CTLE  $T_{p10}$   
 Off

CTLE Type  
Standard

0.5  $A_{DC}$  1.5  $f_{p1}$  GHz  
0.75  $f_z$  GHz 5.0  $f_{p2}$  GHz

Clock Recovery

Bit Rate:  Auto Detect  
Nominal 10 Gb/s

PLL Type:  1  2

7.5 PLL BW MHz  
0.7 PLL Damp  
0 Clk Delay ps

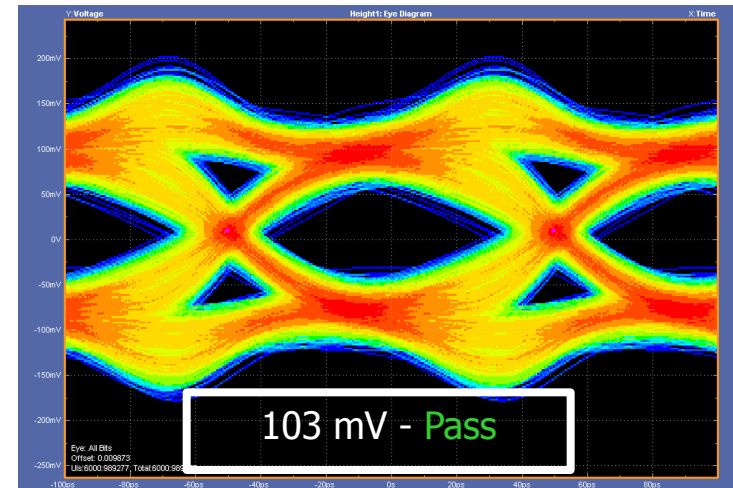
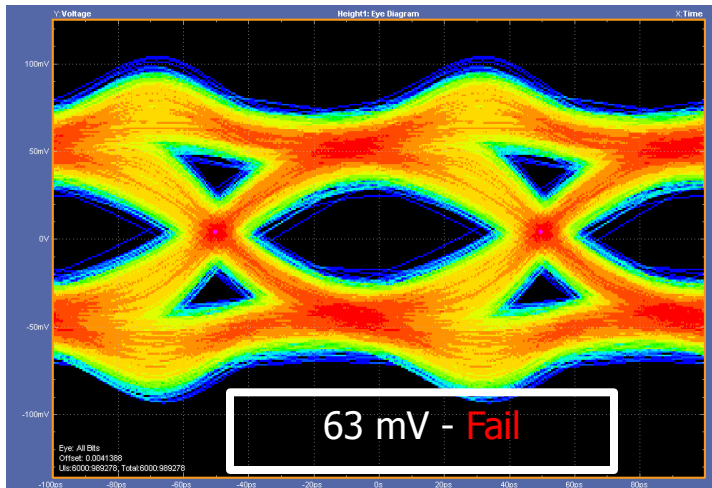
On Equalizer: FFE / DFE  
 Off

FFE/DFE Type Custom Adapt Taps Auto

0 FFE Taps 1 DFE Taps  
1 Sample/bit 0.03 Amplitude  
1 Ref Tap 0 Threshold

Use TrainSeq  Autoset V

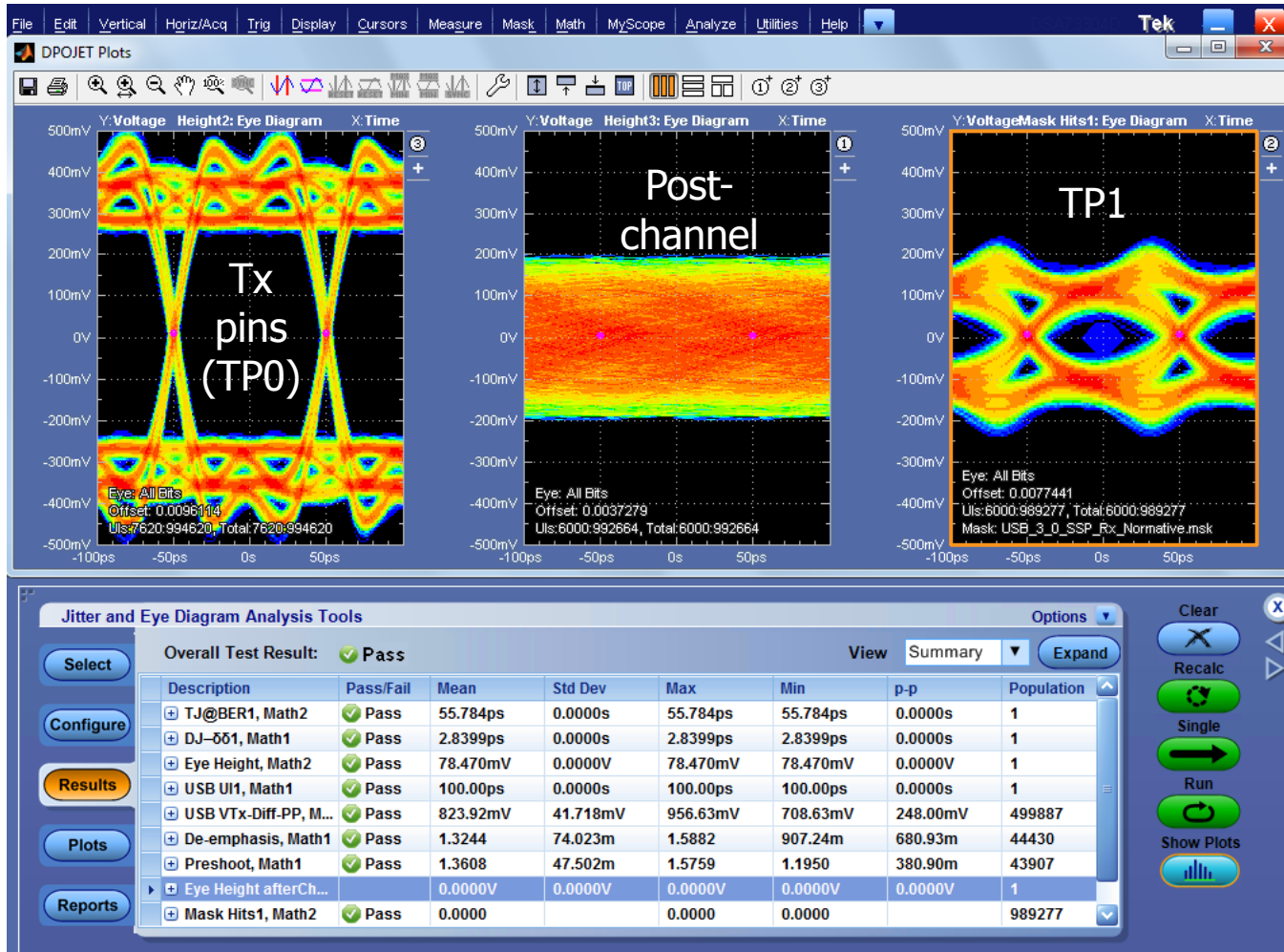
Run Eq  
PCIE Output  
Results  
CTLE  
Plot  
OK





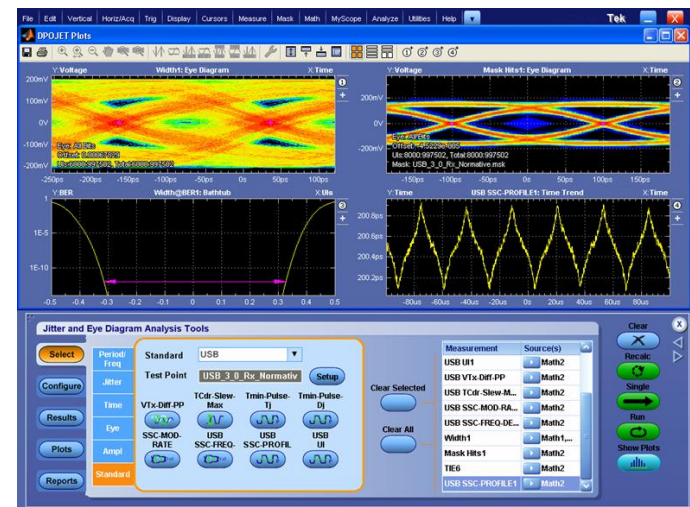
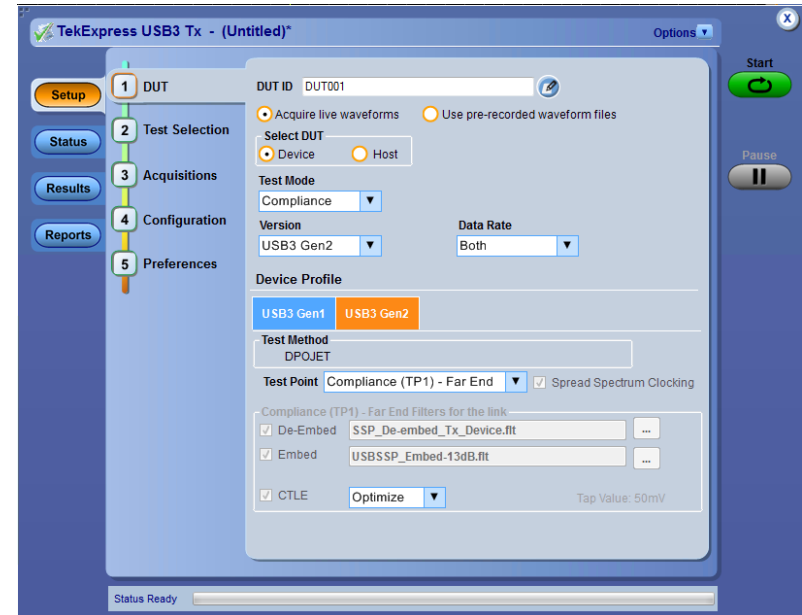
# Transmitter Validation Example - DPOJET

- Measure Eye height and jitter at TP1



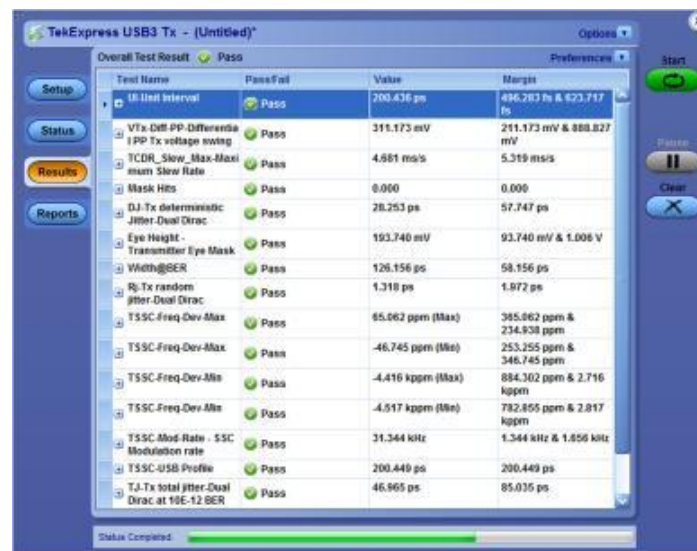
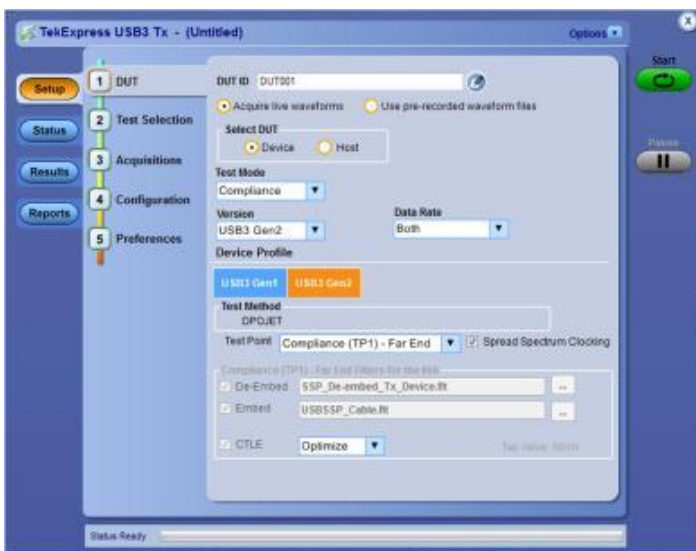
# TekExpress USBSSP-TX Software

- Automates USB 3.1 gen1 & gen2 electrical tests
- Built-in control of LFPS generator for pattern toggle
  - CP0 – CP12
- Use preferred operating mode for your application
  - **Compliance:** Full automation of ping.LFPS, analysis and reporting
  - **User-defined:** Custom channel characterization and test limits
  - **Debug:** DPOJET based manual measurements with expanded jitter analysis and plotting capabilities



# USB 3.1 Recommended Transmitter Solution

- $\geq 23$  GHz BW, 100 GS/sec preferred
- $>10$ M minimum record length allows capture of 1M UI at 100 GS/sec, no interpolation.
- DPOJET for advanced jitter/eye analysis (Option DJA)
- SDLA for channel embedding and cycling through 7 CTLE/1 DFE settings (Option SDLA64)
- TekExpress automation software for USB 3.1 gen1/gen2 physical layer validation (Option USBSSP-TX)

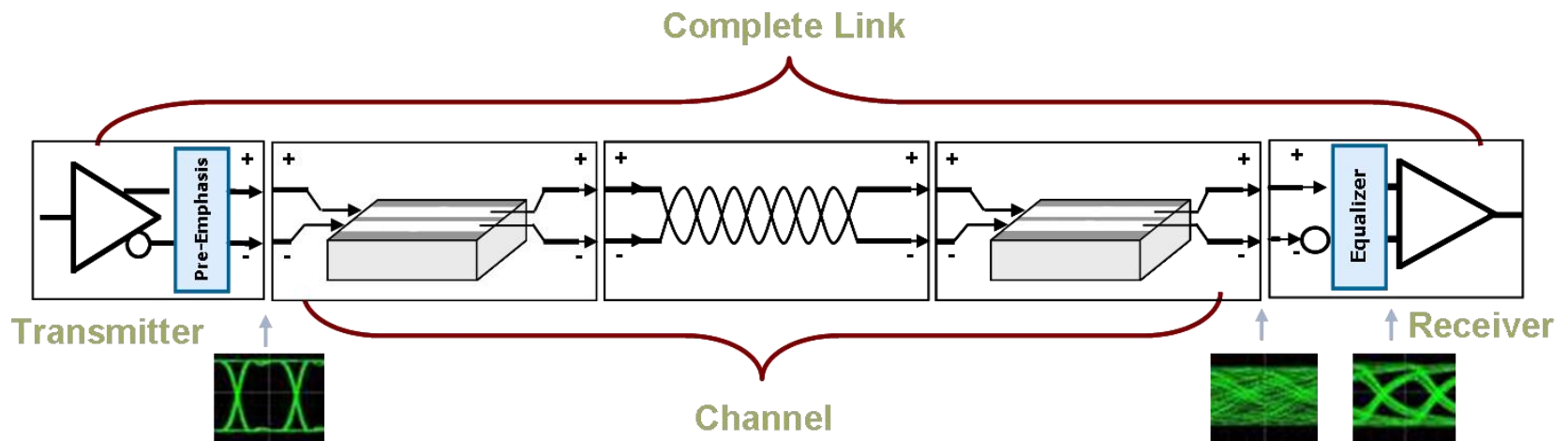


# Receiver Compliance Test

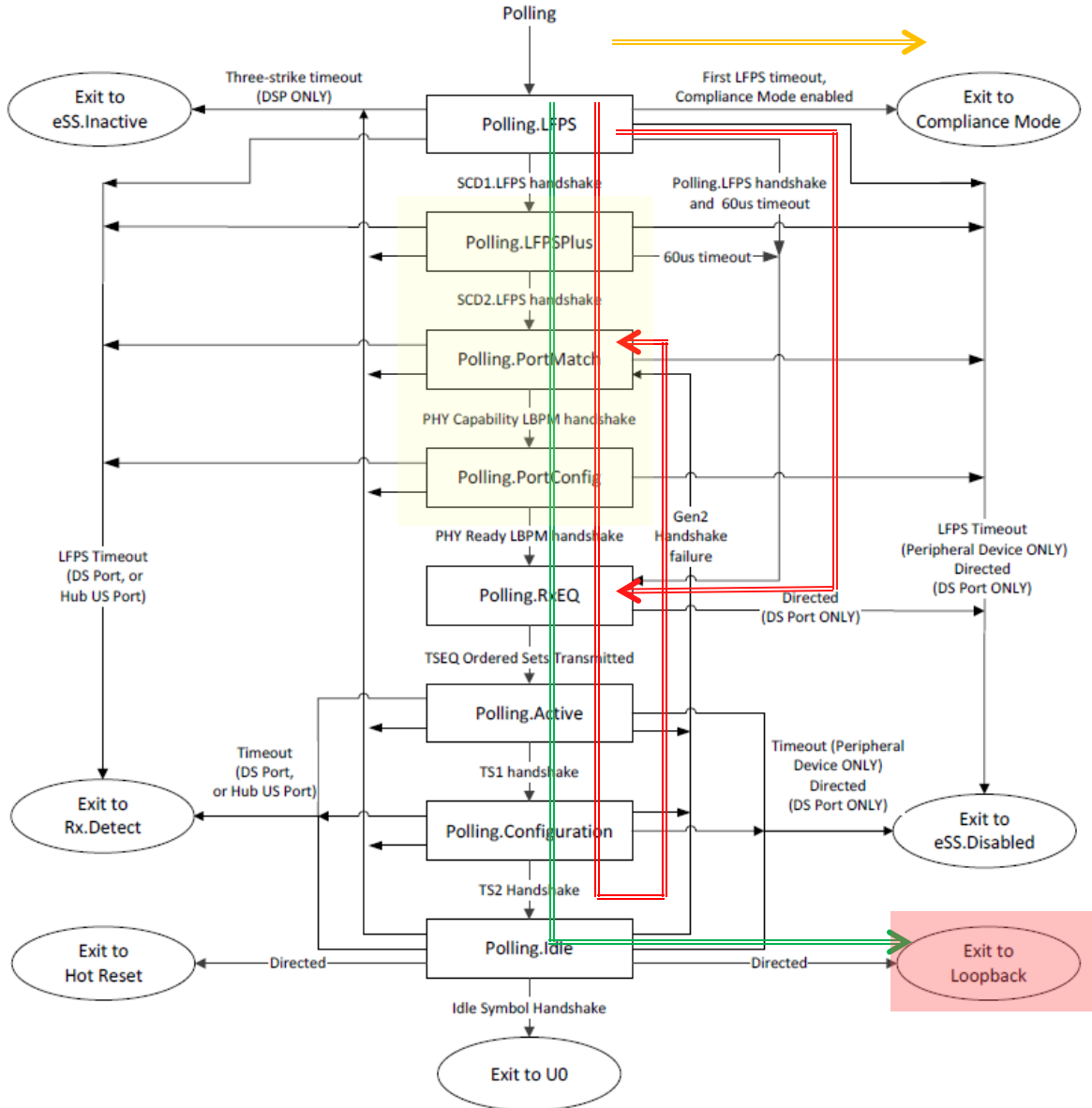


# USB 3.1 Receiver Testing Overview

- A jitter tolerance test is required for certification, though debug and characterization capabilities are needed to ensure that receivers will work in real world conditions
  - Send specific test data patterns to the device-under-test (DUT) through a known channel (fixtures and cables)
  - Add a specific “recipe” of stresses and de-emphasis
  - Command the DUT into loopback mode (far-end retimed)
  - Return “echoed” data to a BERT
  - Detected errors are inferred to be a result of bad DUT receiver decisions



# Polling Sub-states – Loopback



Successful Gen2 link training with loopback asserted – Enter in Loopback mode

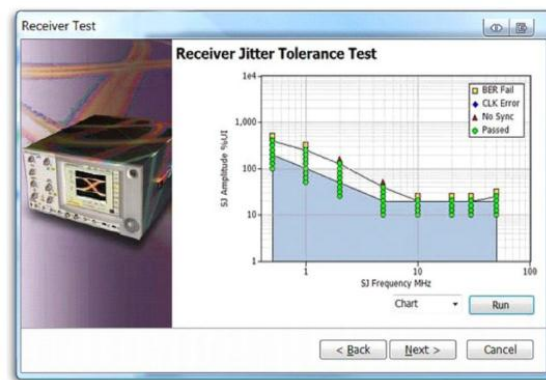
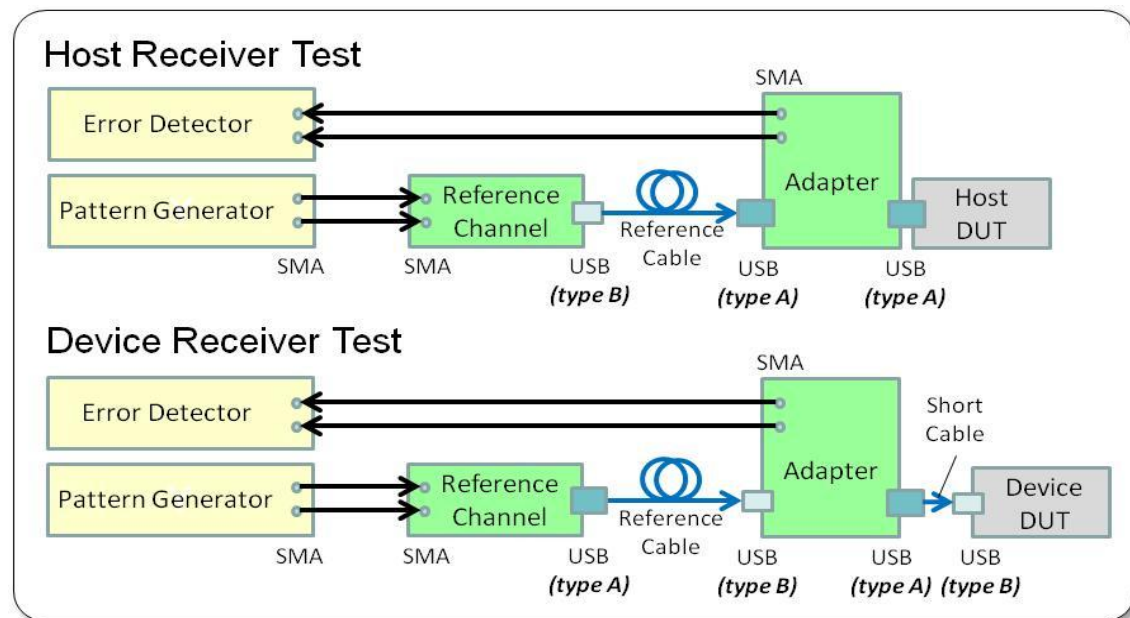
No link partner response – Enter Tx compliance mode

Training failure – Retry at Gen1 rate

LFPS detected but no LFPSPlus - Train at Gen1 rate

# Receiver Testing

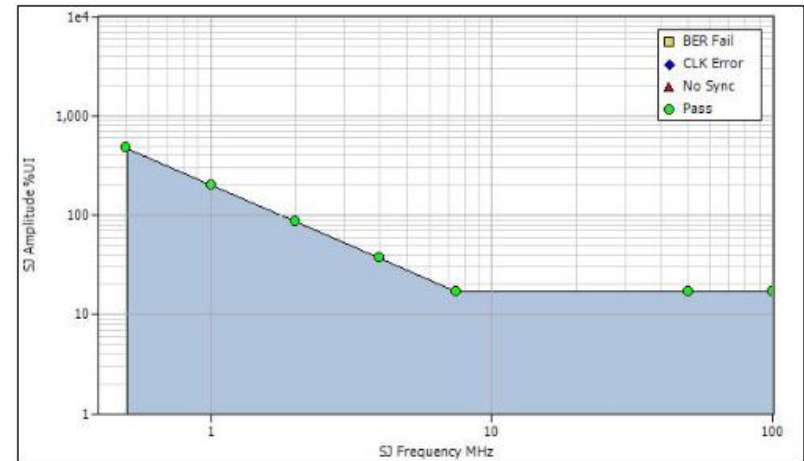
- Jitter Tolerance (JTOL) with swept jitter profile, reference channel
  - Verify CDR tracking and ISI compensation
- Link optimization/training critical
  - No back channel negotiation
- Return “echoed” data to a BERT (loopback)
- Detected errors are inferred to be a result of bad DUT receiver decisions



# Receiver Tolerance Test Overview

- 7 Test Points
- SSC Clocking is enabled
- BER Test is performed at  $10^{-10}$
- Preshoot/De-emphasis enabled
- Stress verified by TJ/Eye Height
- Each SJ term in the table below is tested one at a time after the device is in loopback mode

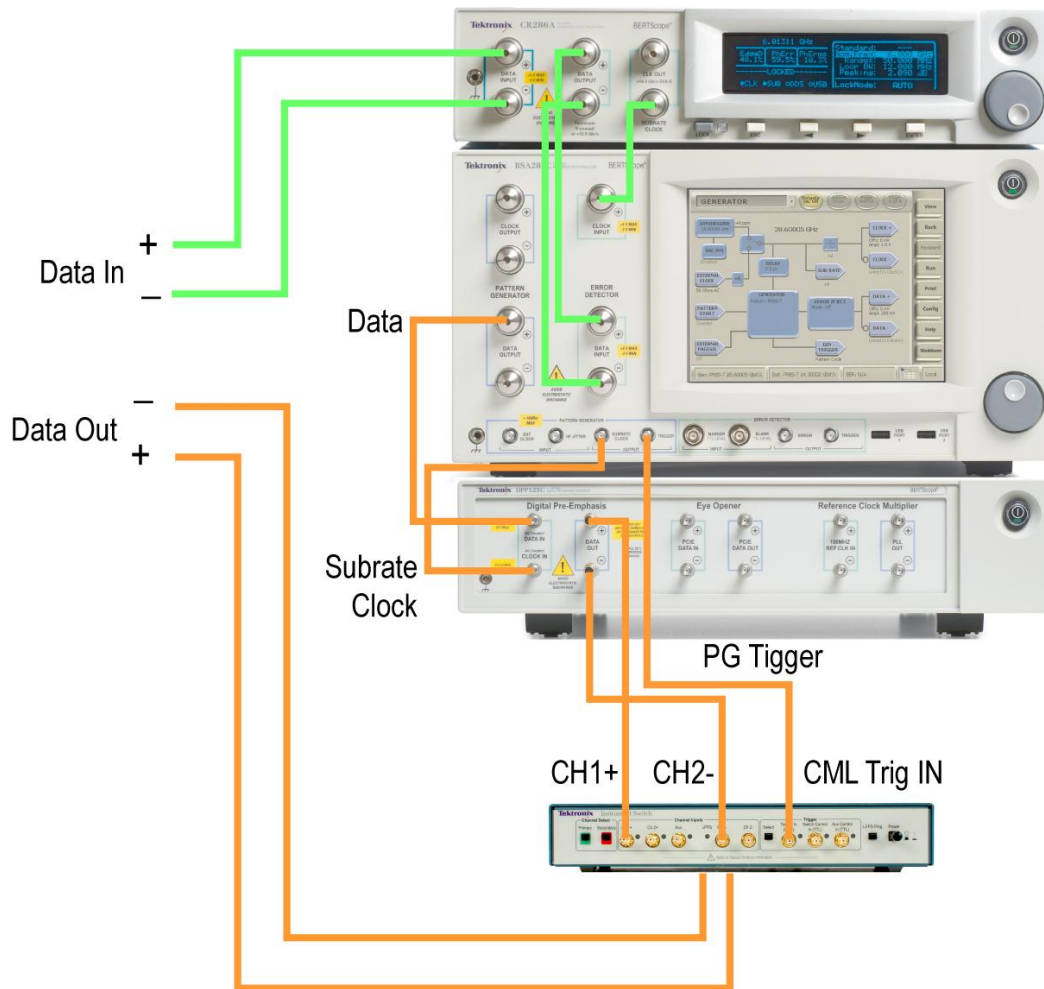
Frequency	SJ	RJ
500kHz	476ps	1.308ps RMS
1MHz	203ps	1.308ps RMS
2MHz	87ps	1.308ps RMS
4MHz	37ps	1.308ps RMS
7.5MHz	17ps	1.308ps RMS
50MHz	17ps	1.308ps RMS
100MHz	17ps	1.308ps RMS



MHZ	Test	Template	Bits	Errors	BER	Status	Margin
0.50	476.00%	476.00%	3.00e010	0	0.00e000	Passed	0.00%
1.00	203.00%	203.00%	3.00e010	0	0.00e000	Passed	0.00%
2.00	87.00%	87.00%	3.00e010	0	0.00e000	Passed	0.00%
4.00	37.00%	37.00%	3.00e010	0	0.00e000	Passed	0.00%
7.50	17.00%	17.00%	3.00e010	0	0.00e000	Passed	0.00%
50.00	17.00%	17.00%	3.00e010	0	0.00e000	Passed	0.00%
100.00	17.00%	17.00%	3.00e010	0	0.00e000	Passed	0.00%



# BERTScope USB 3.1 Receiver configuration solution



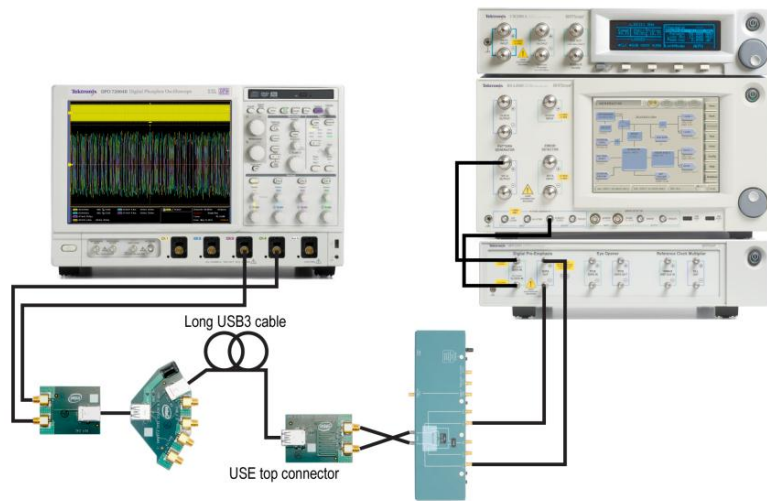
- **CR125A**
  - Clock Recovery
- **BSA125C**
  - BERTScope
- **USB3.1 automation software**
- **DPP125C**
  - De-emphasis
- **USB Switch**
  - Creates LFPS required to initiate Loopback-mode

# USB3.1 Rx compliance

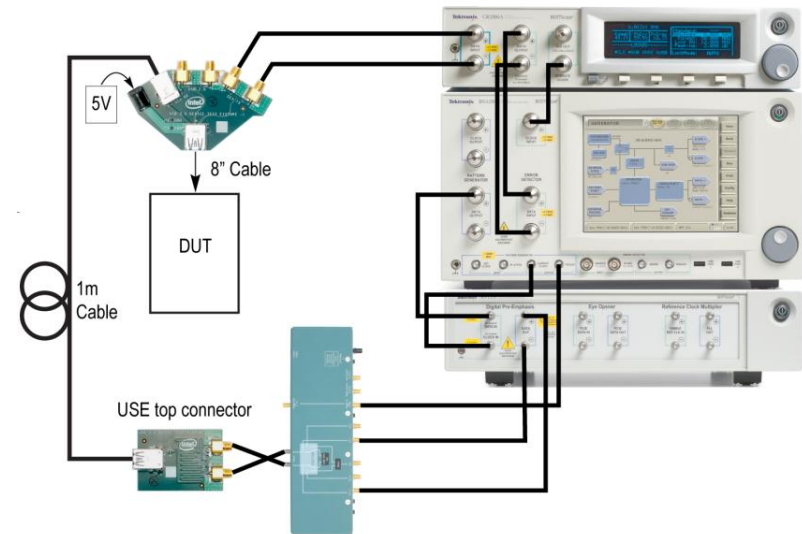
## RX testing using BERTSCOPE

- USB-IF 'Compliance Channel
- Jitter tolerance testing using BERTSCOPE
- Auto Calibration & measurement Tools
- Powerful Jitter insertion function for Developers.

Eye Calibration Cabling Diagram

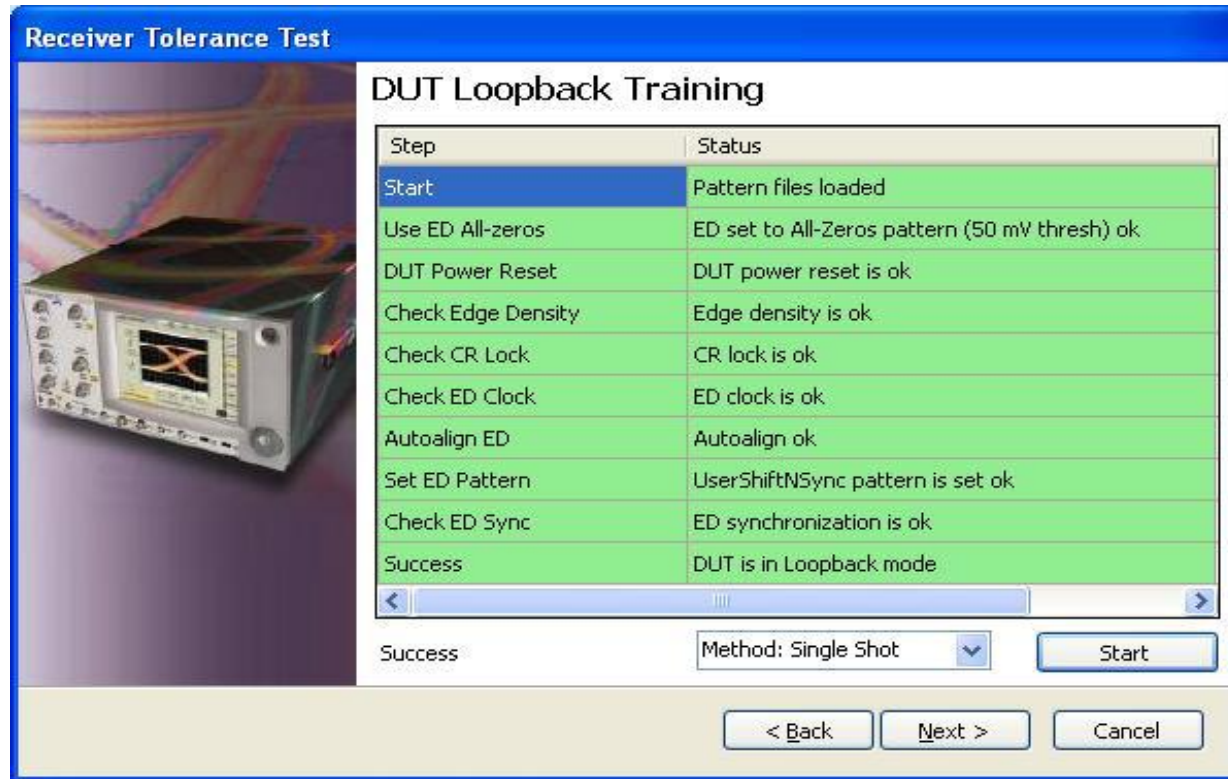


USB3.1\_Rx Calibration Configuration with BERTScope



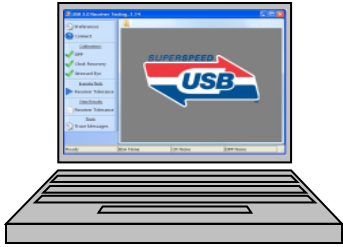
USB3.1\_Rx Testing Configuration with BERTScope

# Loopback Initiation

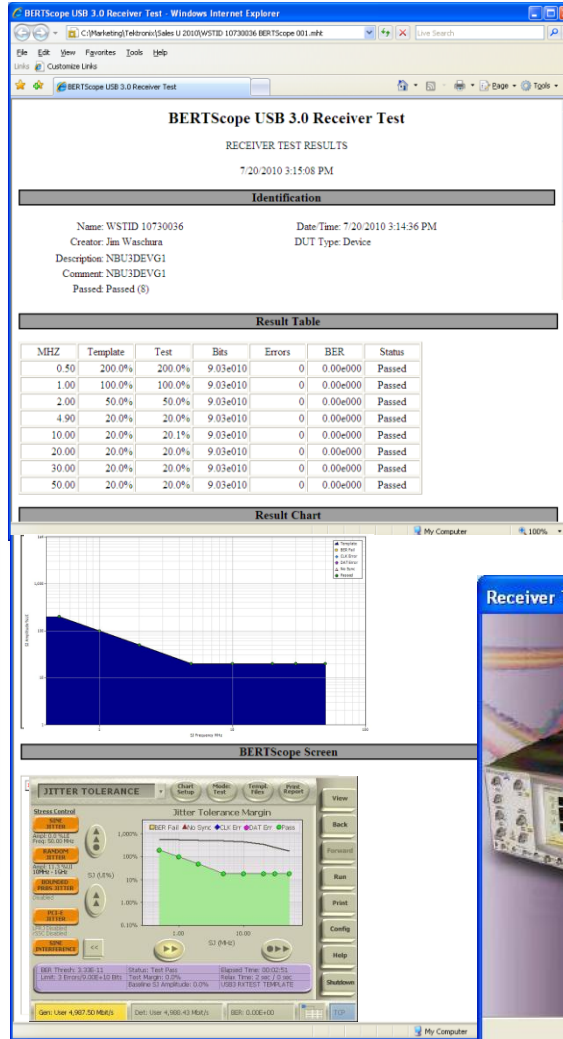
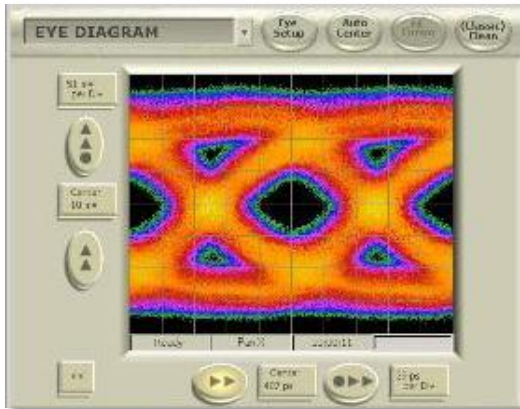


- Loopback initiation prepares devices for receiver testing
- Automation software controls the loopback sequence, eliminating guesswork so users focus on testing and debugging

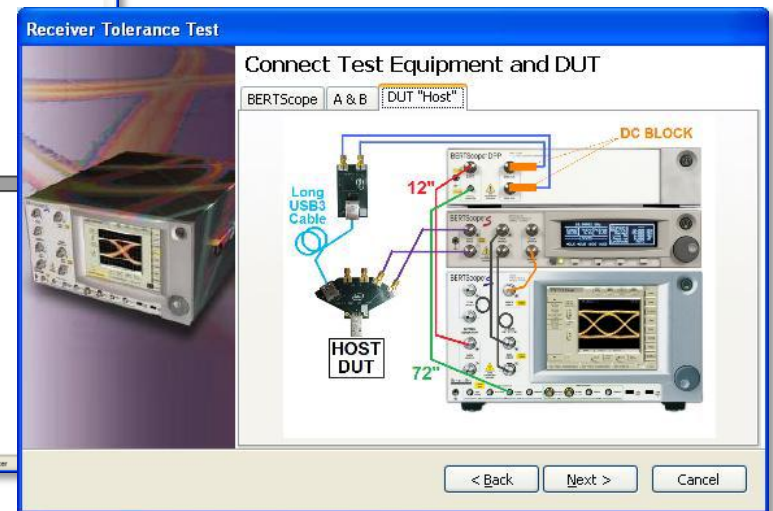
# Automation Software Makes Testing Even Easier



Automation Software



- Results stored to database for easy recall and management
- HTML style test reports
- Cabling diagrams for straightforward setups
- Automated Stressed Eye Calibration



# Summary

- New opportunity for growth with USB 10 Gb/s
- Adds additional challenges beyond legacy requirements (backwards compatibility)
- Higher performance, more complex design but feasible within current infrastructure
- Extensive PHY validation tools for early designs
  - New USB SSP DPOJET setups for Tx validation
  - BERTScope USB library with JTOL templates
  - DSA8300 Sampling oscilloscope for channel characterization
  - Test procedures documented in Methods of Implementation (MOI)



# Tektronix MHL 3.2 TX,RX Solution

# MHL – CTS 3.2

- MHL Consortium and Tektronix has worked together on the 3.0 version MHL specifications.
  - **Data rate changes to 6Gbps.**
  - **MHL Clock is no longer common mode but transmitted on eCBUS**
  - eCBUS has bi-directional ecbus data and clock
  - New test procedures for Source, Sink and Dongle
  - Most of the CTS 2.1 tests need to be used to ensure backward compatibility exists.



# MHL 3.0/CTS3.2

## - Signaling

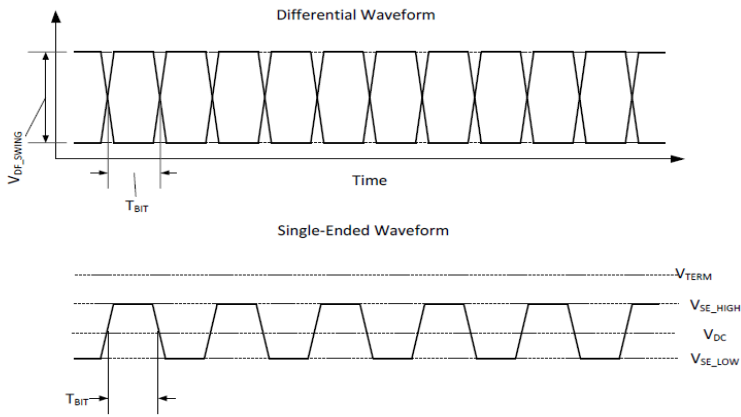


Figure 16-4. Voltage and Timing Parameters of a Differential Signal and a Single-Ended Signal

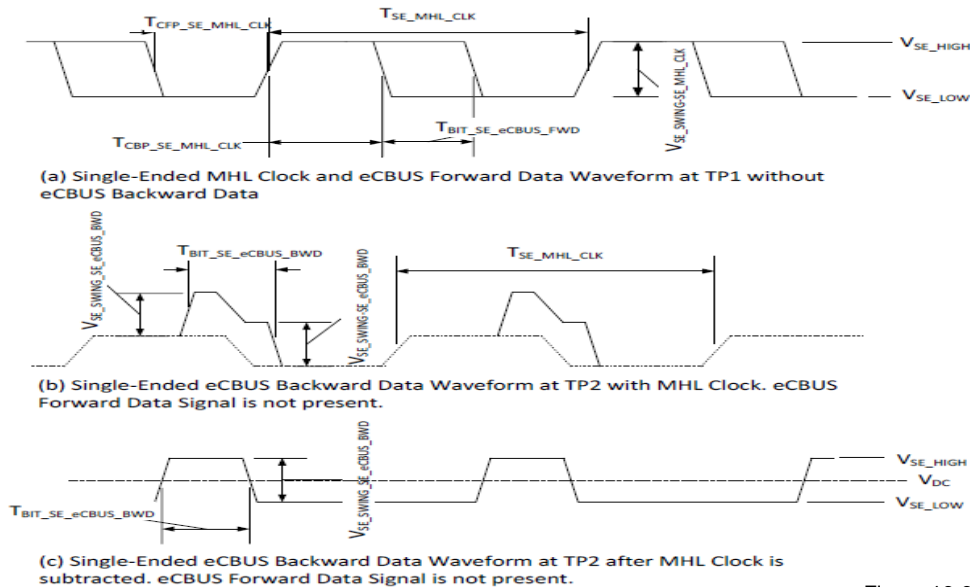


Figure 16-5. Voltage and Timing Parameters of a Single-ended MHL Clock and eCBUS Forward and Backward Signals

- VDF\_SWING in Figure 16-4 represents
  - VDF\_SWING\_DF\_TMDS\_DATA
  - VDF\_SWING\_DF\_MHL\_CLK
  - VDF\_SWING\_DF\_eCBUS\_FWD
  
- VSE\_HIGH represents
  - VSE\_HIGH\_DF\_TMDS\_DATA
  - VSE\_HIGH\_DF\_MHL\_CLK
  - VSE\_HIGH\_DF\_eCBUS\_FWD
  
- VSE\_LOW represents
  - VSE\_LOW\_DF\_TMDS\_DATA
  - VSE\_LOW\_DF\_MHL\_CLK
  - VSE\_LOW\_DF\_eCBUS\_FWD

Figure 16-6. Voltage and Timing Parameters of a Differential MHL Clock and eCBUS Forward and Backward Signals



# MHL 3.0/CTS3.2

## - EQ and Cable Emulator

### ■ Reference Cable Equalizer

- Two reference cable equalizers are used
- Used to produce the MHL eye diagram and clock jitter measurements at TP2 for TMDS and eCBUS forward signals,
- Used to produce at TP1 for eCBUS backward signals

### > 6Gbps reference cable equalizer

- Shall meet the transfer function shown in Figure 16-15 (Differential)
- Applied to the TMDS signal at the 6Gbps data rate.

### > MHL 2.1 reference cable equalizer

- Applied to 3Gbps and to 1.5Gbps TMDS signals, and to eCBUS-D signals
- Applied to the single-ended MHL clock signal when the single-ended MHL clock signal is tested for clock jitter, TMDS eye diagram, and eCBUS-S data eye diagram tests.

### ■ Worst Case Cable Emulator

- The worst case cable emulator is used to perform TP2 tests for TMDS, eCBUS Forward signals and TP1 tests for eCBUS Backward signal

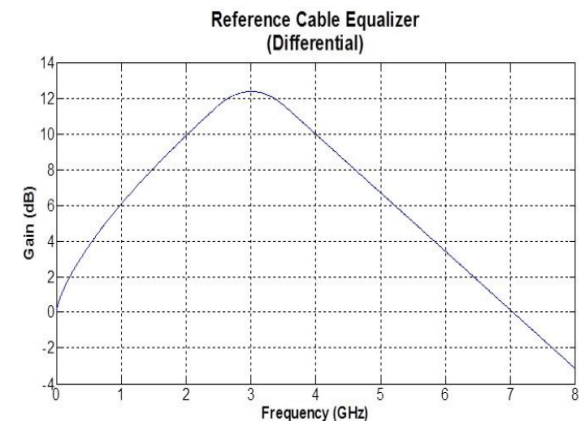
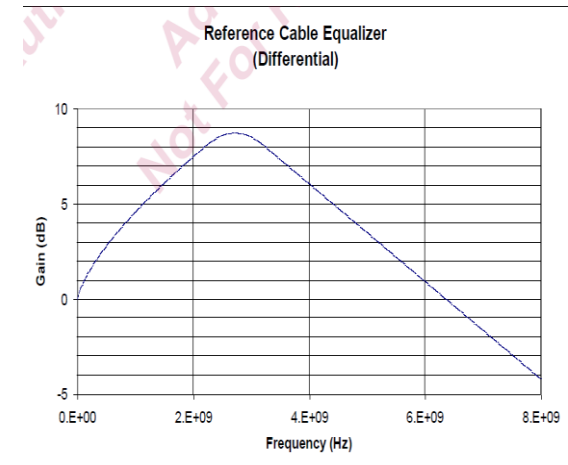


Figure 16-15. 6Gbps Reference Cable Equalizer Gain Curve

# Tektronix MHL 3.2 CTS Tx Solution- Test Details

DUT	Type	TEST	
<b>MHL Source</b>	<b>Output</b>	3.7.2.1	Single-Ended high level output voltage: Differential TMDS Data+/-
		3.7.2.2	Single-Ended low level output voltage: Differential TMDS Data+/-
		3.7.2.5	Differential output swing voltage: Differential TMDS Data
		3.7.2.7	Single-Ended high level output voltage: Single-Ended MHL CLK, Single-Ended eCBUS Forward
		3.7.2.8	Single-Ended low level output voltage: Single-Ended MHL CLK, Single-Ended eCBUS Forward
		3.7.2.9	Single-Ended output swing voltage: Single-Ended MHL CLK, Single-Ended eCBUS Forward
		3.7.2.13	Rise Time, Differential TMDS Data
		3.7.2.14	Fall Time, Differential TMDS Data
		3.7.2.17	Peak-Peak Amplitude: Differential TMDS Data
		3.7.2.20	Single_Ended MHL Clock Frequency
		3.7.2.23	Rise Time: Single-ended MHL Clock
		3.7.2.24	Fall Time: Single-ended MHL Clock, Single-ended eCBUS Forward
		3.7.7.25	Peak-Peak Amplitude, eCBUS-S Forward
		3.7.7.26	Single-Ended MHL Clock Jitter
		3.7.7.27	MHL3 Differential Eye Diagram Mask at TP2 for TMDS Data
	3.7.2.29	MHL3 Single-ended Eye Diagram Mask at TP2 for Single-Ended eCBUS FWD Data	
	3.7.2.33	Single-Ended input swing voltage: Single-Ended eCBUS Backward	
	3.7.2.36	MHL3 Single-Ended Eye Diagram Mask at TP1 for Single-Ended eCBUS BWD Data	
	3.7.2.37	TMDS+ and TMDS- Differential Impedance through Connections TMDS+ and TMDS- Differential Impedance at Termination	
	3.7.2.39	eCBUS Single-Ended Impedance through Connections eCBUS Single-Ended Impedance at Termination	

# Tektronix MHL 3.2 CTS Rx Solution- Test Details

DUT	Type	TEST	
MHL Sink	Input	4.7.2.3	Differential input swing voltage: Differential TMDS Data
		4.7.2.6	Single-Ended input swing voltage: Single-Ended MHL CLK, Single-Ended eCBUS Forward
		4.7.2.7	Differential Intra-Pair Skew: Differential TMDS Data +/-
		4.7.2.10	Jitter Tolerance of Single-Ended MHL CLK, eCBUS-S FWD Data and Differential TMDS Data
	Output	4.7.2.14	Single-Ended high level output voltage:Single-Ended eCBUS Backward
		4.7.2.15	Single-Ended low level output voltage:Single-Ended eCBUS Backward
		4.7.2.16	Single-Ended output swing voltage:Single-Ended eCBUS Backward
		4.7.2.20	Rise time, Single-Ended eCBUS Backward
		4.7.2.21	Fall Time, Single-Ended eCBUS Backward
		4.7.2.22	Peak-peak Amplitude, eCBUS-S Backward
		4.7.2.24	MHL3 Eye Diagram Mask at TP1 for Single-Ended eCBUS Backward Data
	Impedance	4.7.2.25	TMDS+ and TMDS- Differential Impedance through Connections
			TMDS+ and TMDS- Differential Impedance at Termination
4.7.2.27		eCBUS Single-Ended Impedance through Connections	
	eCBUS Single-Ended Impedance at Termination		

# Tektronix MHL 3.2 CTS Transmitter/Receiver Solution

## Transmitter Tests

- AV Link Data tests(TMDS)
- Clock Tests
- eCBUS FWD Tests
- eCbus BWD Tests

## Receiver Tests

- SJT
- Intra pair skew
- eCBUS FWD Tests
- eCbus BWD Tests

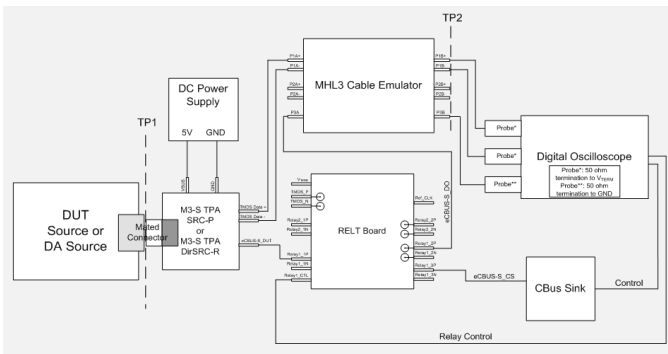
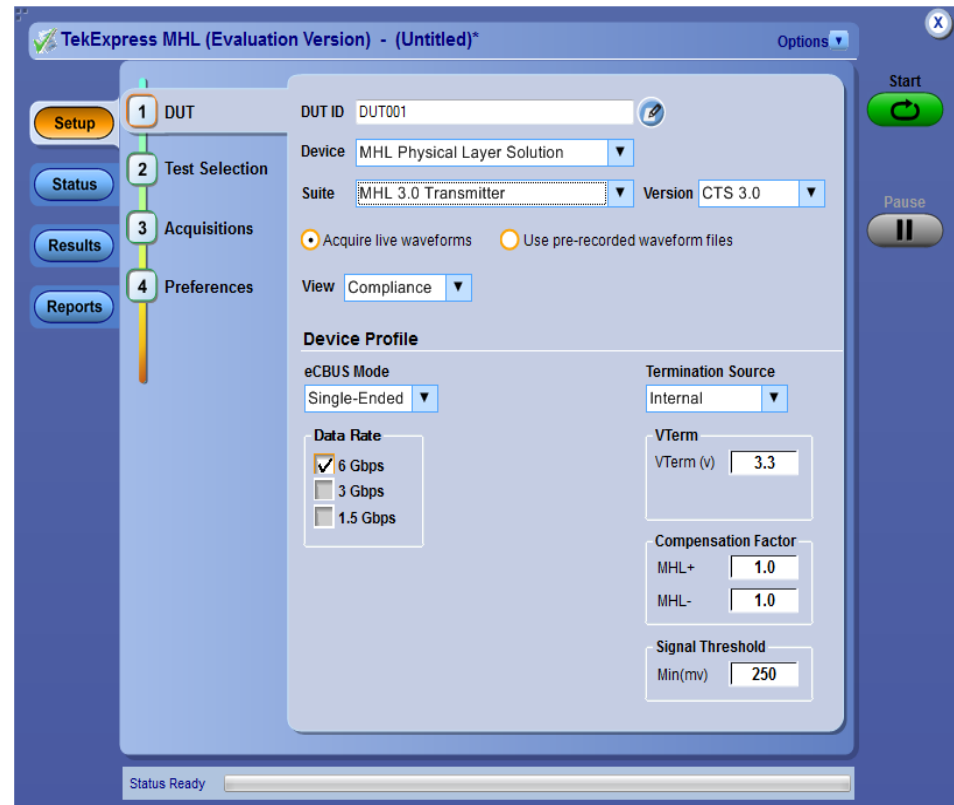


Figure 3-2. Test configuration at TP2 for source TMDS output and eCBUS-S FWD output.



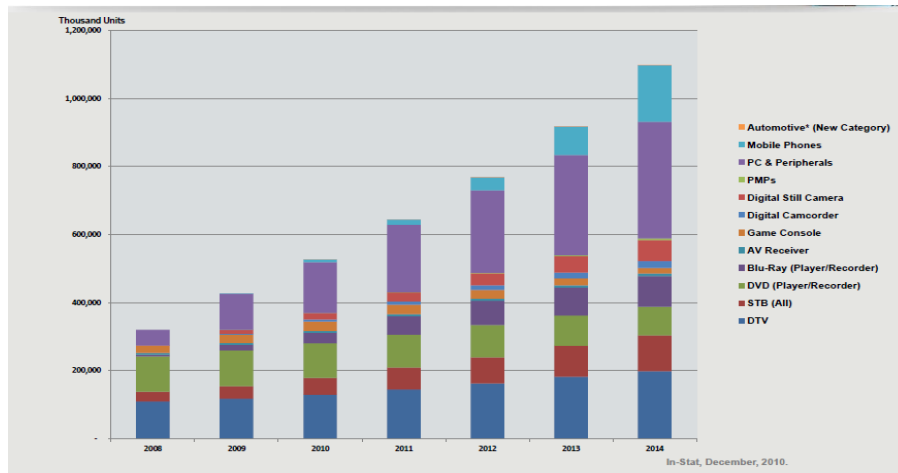
## HDMI2.0 TX,RX Solution

–High Definition Multimedia Interface



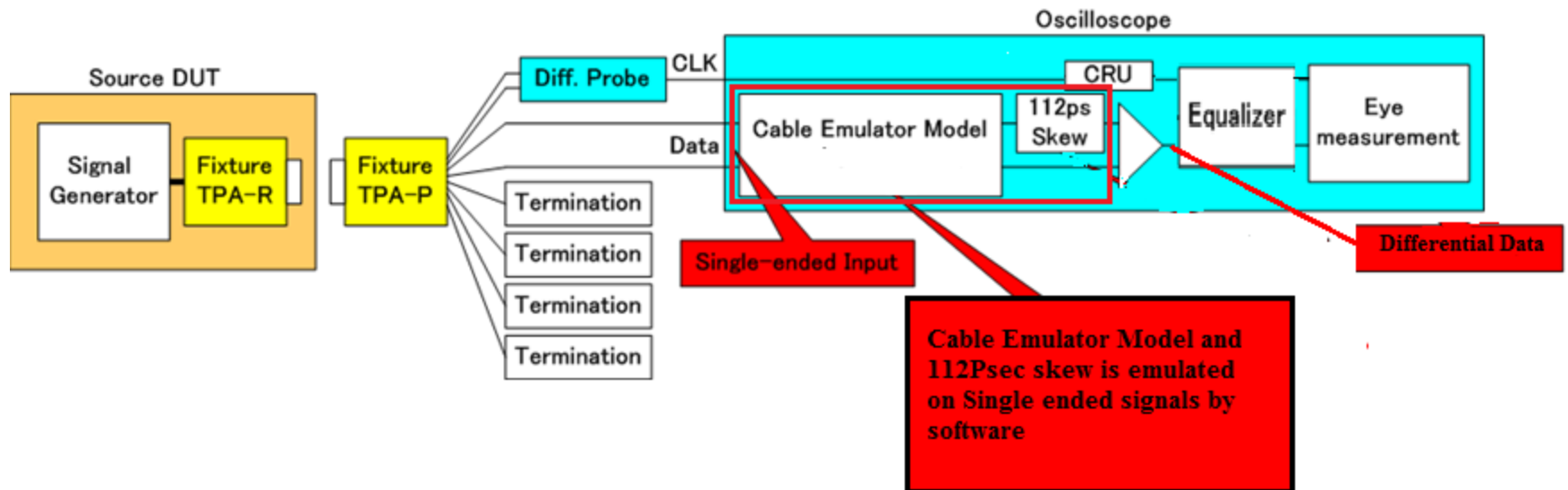
# Proposed HDMI 2.0 features change

- Uses same Cat 2 Cable and HDMI 1.4b connector
- Support 4K 2K 4:4:4 60 Hz – 594Mhz
- Support 4K 2K 4:2:0 – 297Mhz
- Direct Attach device support
- Low level Bit error rate testing
- Scrambling is likely to be introduced for rates >340Mcps.



# Source Testing (1.4b Vs 2.0 )

- Most Source tests are likely to be same as HDMI 1.4b but for Eye Diagram test.
- Source Eye Diagram test is measured at TP2\_EQ with Single ended testing
- TP2 is the signal after passing along a worst cable.
  - Worst cable has worst attenuation and skew of 112ps.
- Min 8GHz scope to 16GHz scope
- Fixtures and Probes



# Likely Source Electrical tests

Test ID HF1-1: Source TMDS Electrical – 340-600Mcsc –  $V_L$

Test ID HF1-2: Source TMDS Electrical – 340-600Mcsc –  $T_{RISE}$ ,  $T_{FALL}$

Test ID HF1-3: Source TMDS Electrical – 340-600Mcsc – Inter-Pair Skew

Test ID HF1-4: Source TMDS Electrical – 340-600Mcsc – Intra-Pair Skew

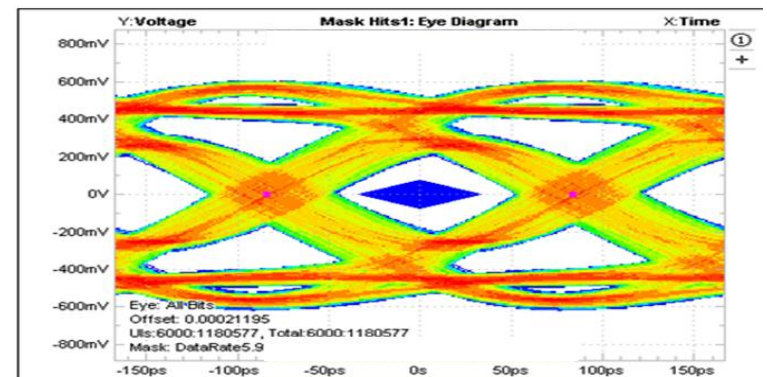
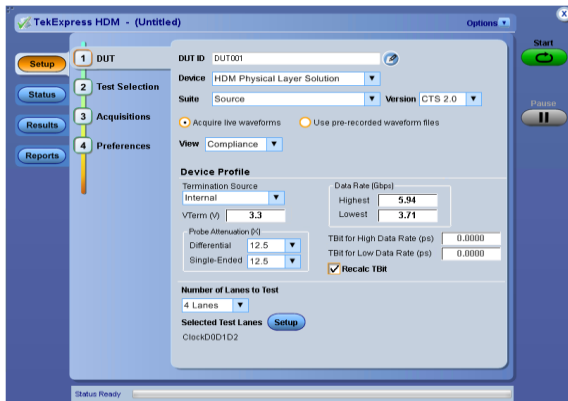
Test ID HF1-5: Source TMDS Electrical – 340-600Mcsc – Differential Voltage

Test ID HF1-6: Source TMDS Electrical – 340-600Mcsc – Clock Duty Cycle

Test ID HF1-7: Source TMDS Electrical – 340-600Mcsc – Clock Jitter

Test ID HF1-8: Source TMDS Electrical – 340-600Mcsc – Data Eye Diagram

Test ID HF1-9: Source TMDS Electrical – 340-600Mcsc – Differential Impedance

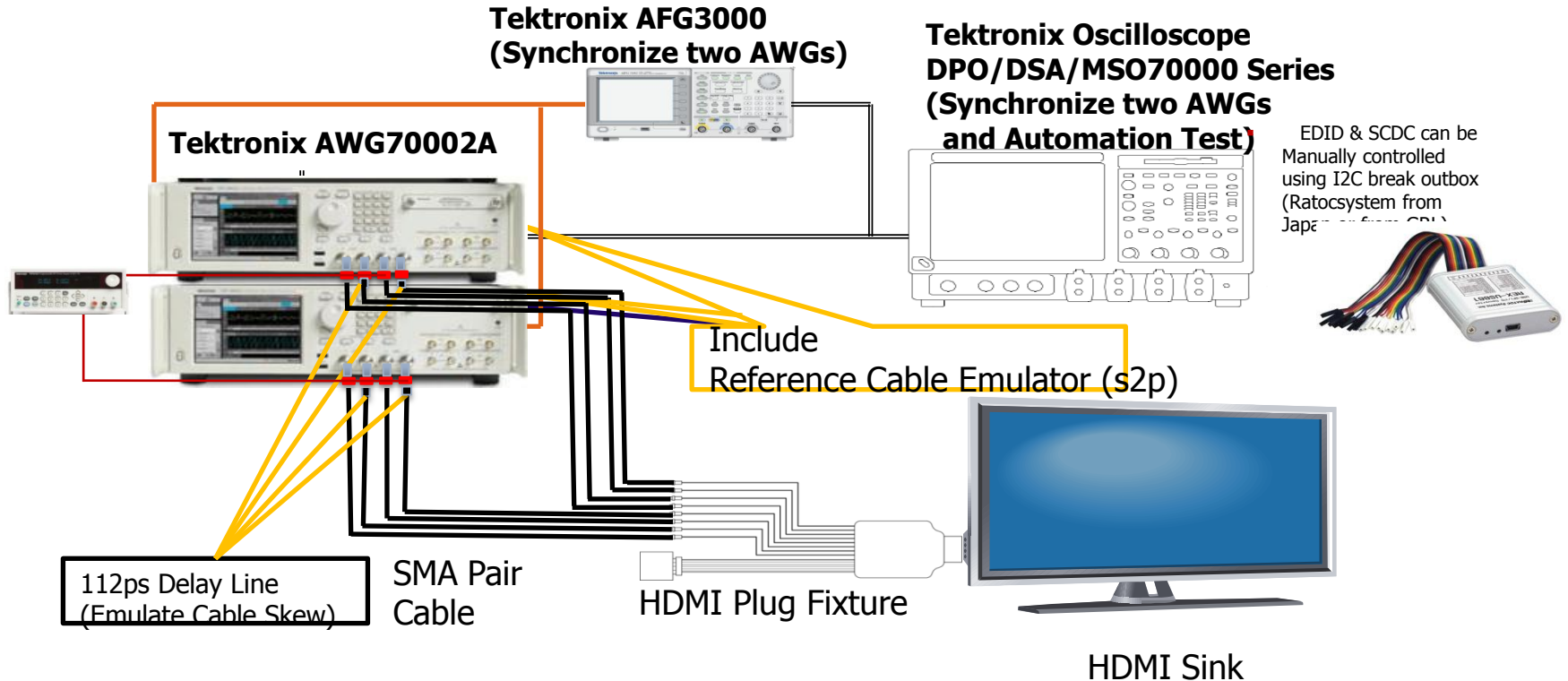


TP2 Source Eye for HDMI 2.0 6G signal



# HDMI 2.0 Sink Test setup –Direct Synthesis

- **Test ID HF2-1: Sink TMDS Electrical – 340-600Mcsc – Min/Max Differential Swing Tolerance**
- **Test ID HF2-2: Sink TMDS Electrical – 340-600Mcsc – Intra-Pair Skew**
- **Test ID HF2-3: Sink TMDS Electrical – 340-600Mcsc – Jitter Tolerance**
- **Test ID HF2-4: Sink TMDS Electrical – 340-600Mcsc – Differential Impedance**  
(performed using sampling scope)



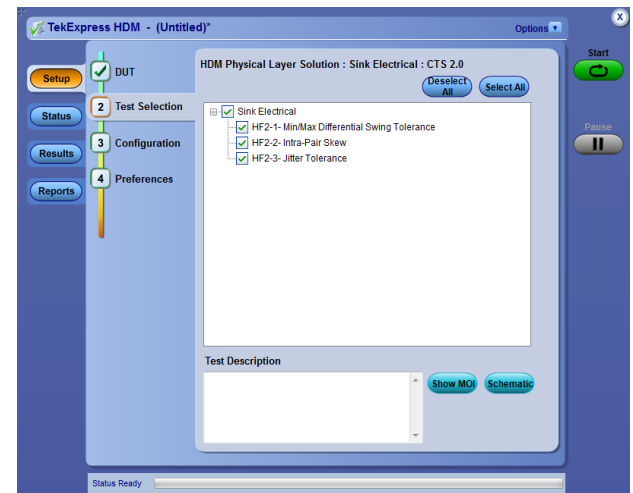
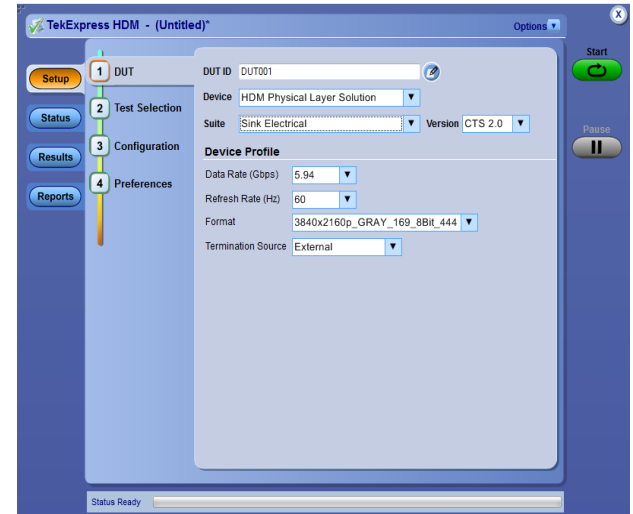
# Source Sink Testing 1.4b Vs 2.0

## SOURCE

- DPO/DSA /MSO 70164C/D with 10XL-Minimum 16GHz BW
- Opt HDM
- Opt HT3 for 1.4 testing.
- HDMI 2.0 Fixture set( Bitifeye for now later will add Wilder)
- P7313SMA probes –Quantity 4

## SINK

- Jitter Tolerance test needs +ve and –ve lanes tested with 112ps delay line
- Rest of the tests is similar to HDMI 1.4b tests
- 1.4b CTS test is a pre-requisite for HDMI 2.0
- Need AWG 70002A for HDMI 2.0 Compliance and Margin needs while AWG7122C is suitable for HDMI 2.0 Compliance testing..
- Min 8GHz scope to 16GHz scope
- Fixtures and Probes
- HDM and HDM-DS Software (TekExpress Based)





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